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(54) **COMPACT, INTERLEAVED RADIATION SOURCES**

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G01V 5/00 (2006.01)
G21K 1/093 (2006.01)
(Continued)

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CPC **G01V 5/0091** (2013.01); **G01N 23/06** (2013.01); **G01V 5/0041** (2013.01); **G21K 1/093** (2013.01); **H01J 35/14** (2013.01)

(58) **Field of Classification Search**
CPC G01V 5/0091; G01V 5/0041; H01J 35/14; G01N 23/06; G21K 1/093
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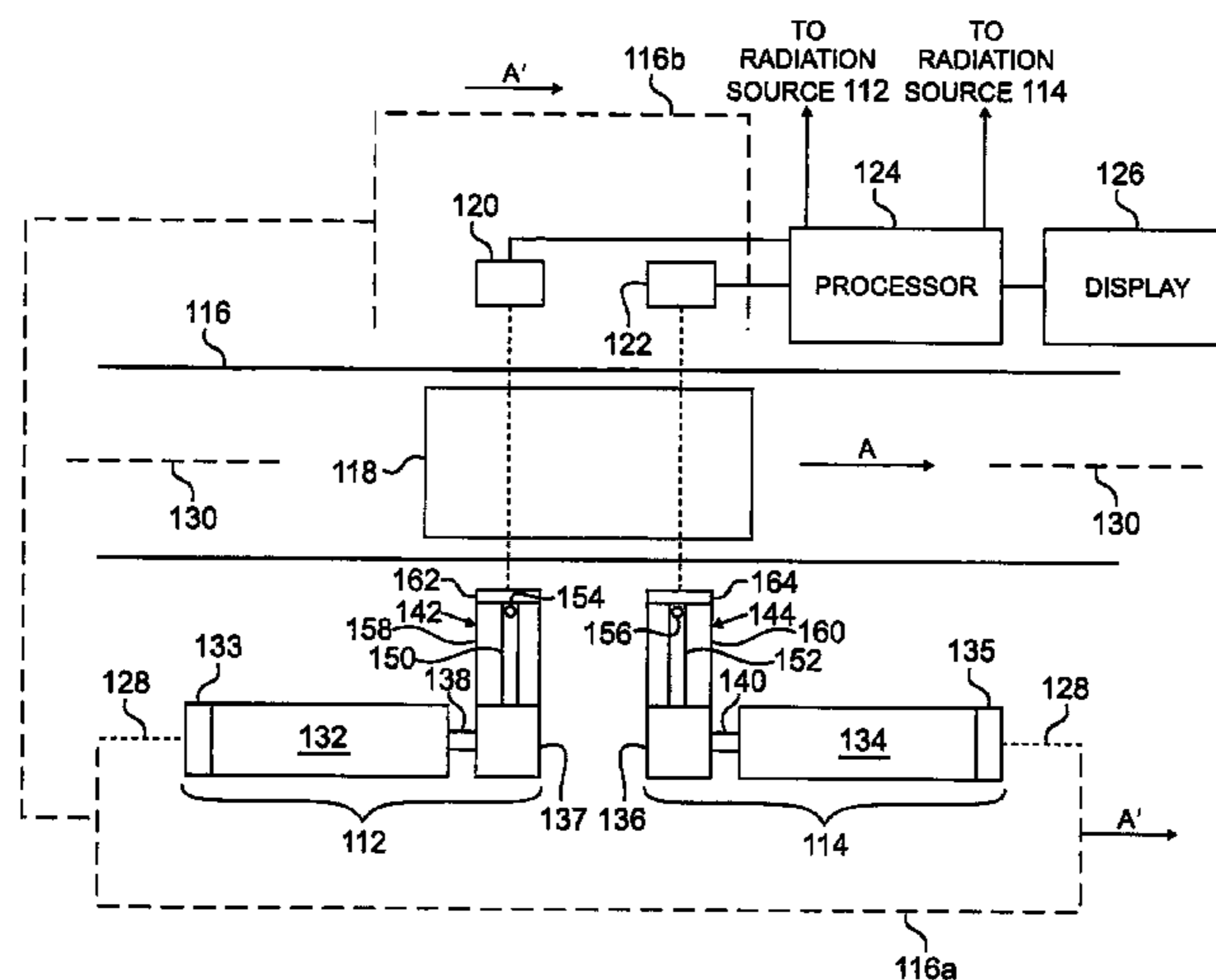
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(57) **ABSTRACT**

Compact, dual energy radiation scanning systems are described comprising two particle beam accelerators, each configured to accelerate charged particles to different energies, positioned parallel to a direction of movement of an object to be inspected. The accelerator may be positioned perpendicular to a plane of the conveying system, instead. Bend magnet systems bend each charged particle beam toward a respective target. Alternatively, a single dual energy accelerator capable of accelerating charged particles to at least two different energies is positioned parallel to the direction of movement of the object, or perpendicular to a plane of the conveying system. A single bend magnet system is provided to bend each accelerated charged particle beam toward the same target. The particle beams may be bent through an orbit chamber. Two separate passages may be defined through at least part of the orbit chamber, one for charged particles having each energy.

23 Claims, 12 Drawing Sheets



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of application No. 12/313,752, filed on Nov. 24, 2008, now Pat. No. 8,198,587.

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H01J 35/14 (2006.01)

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See application file for complete search history.

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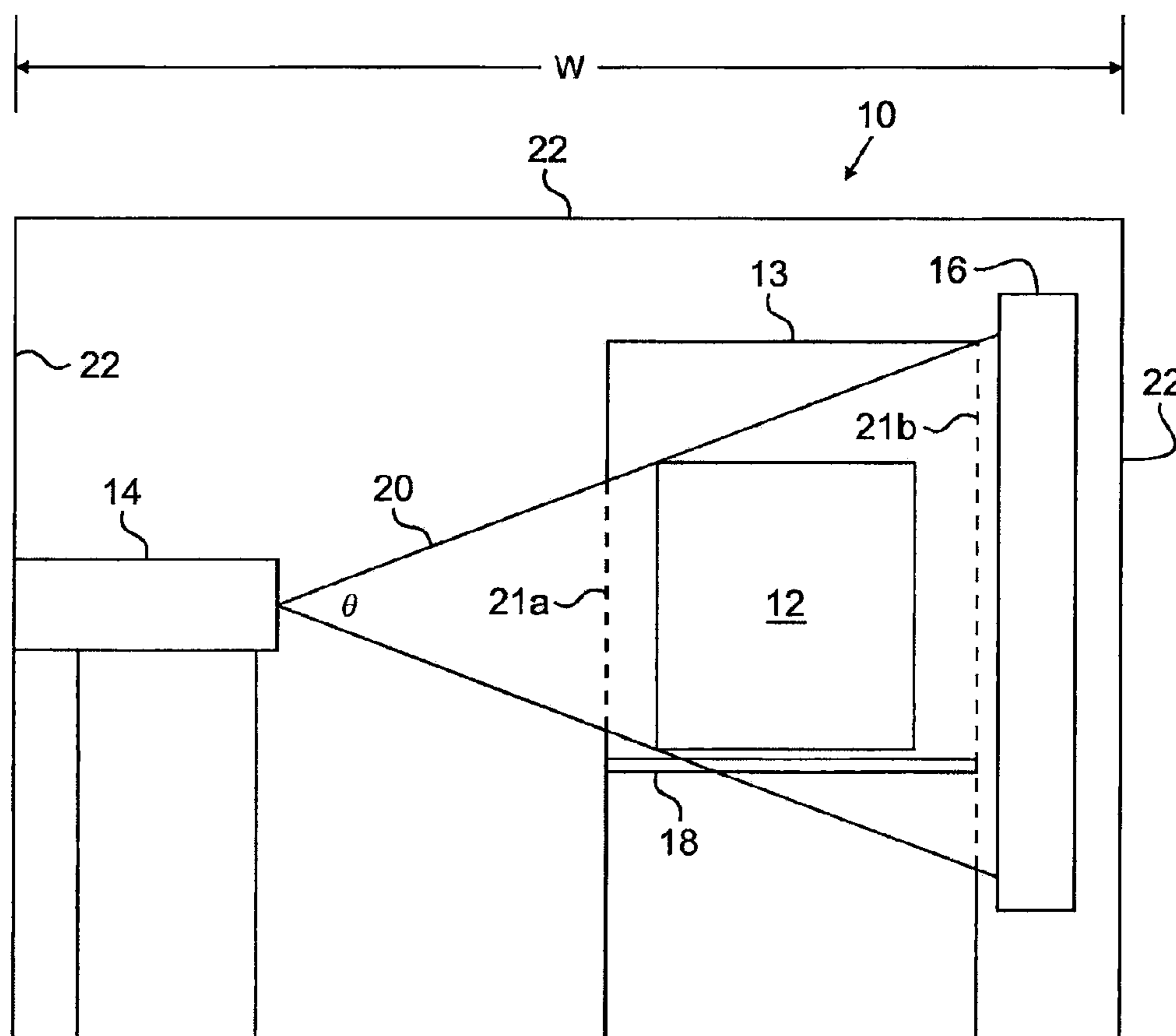


FIG. 1
(PRIOR ART)

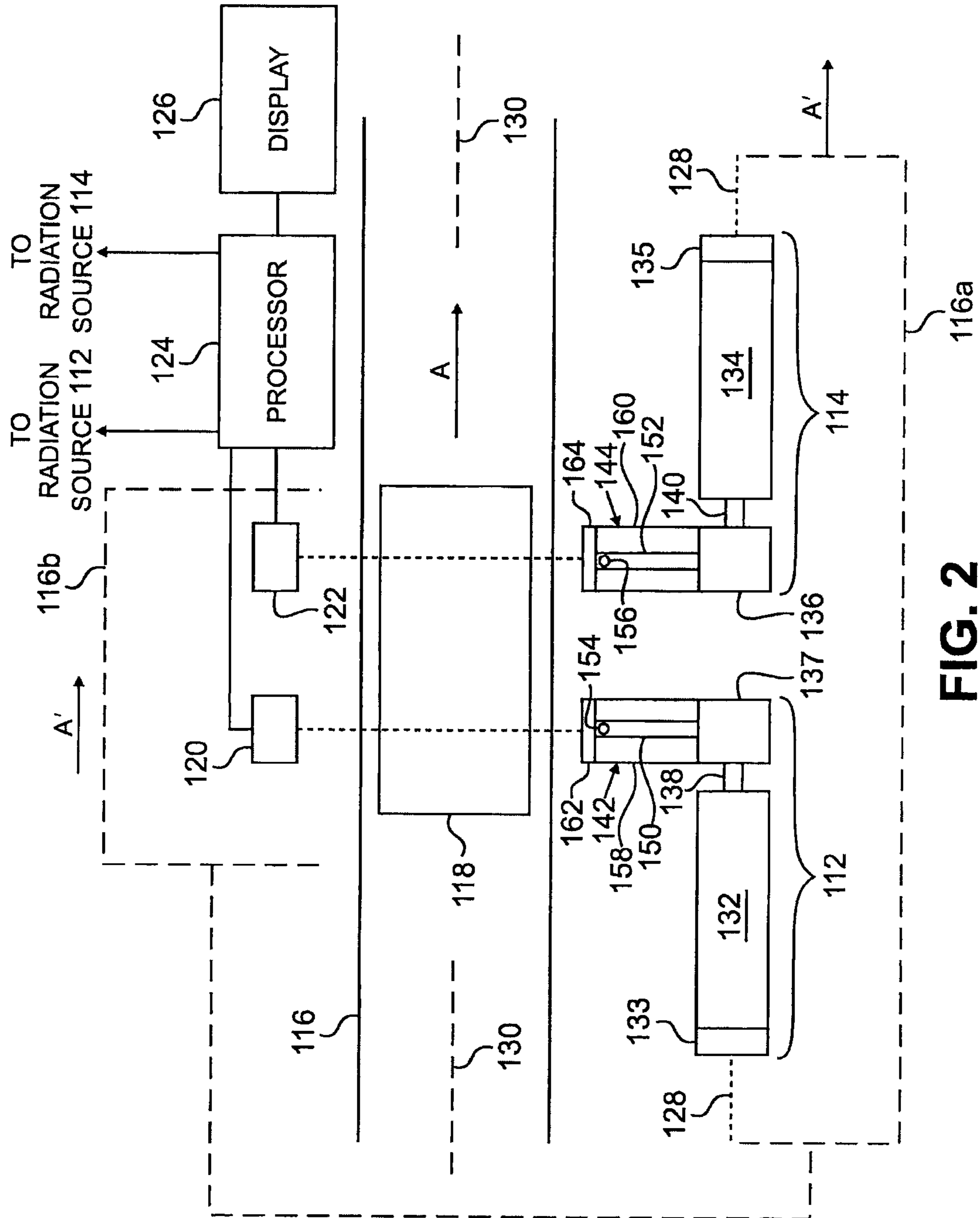
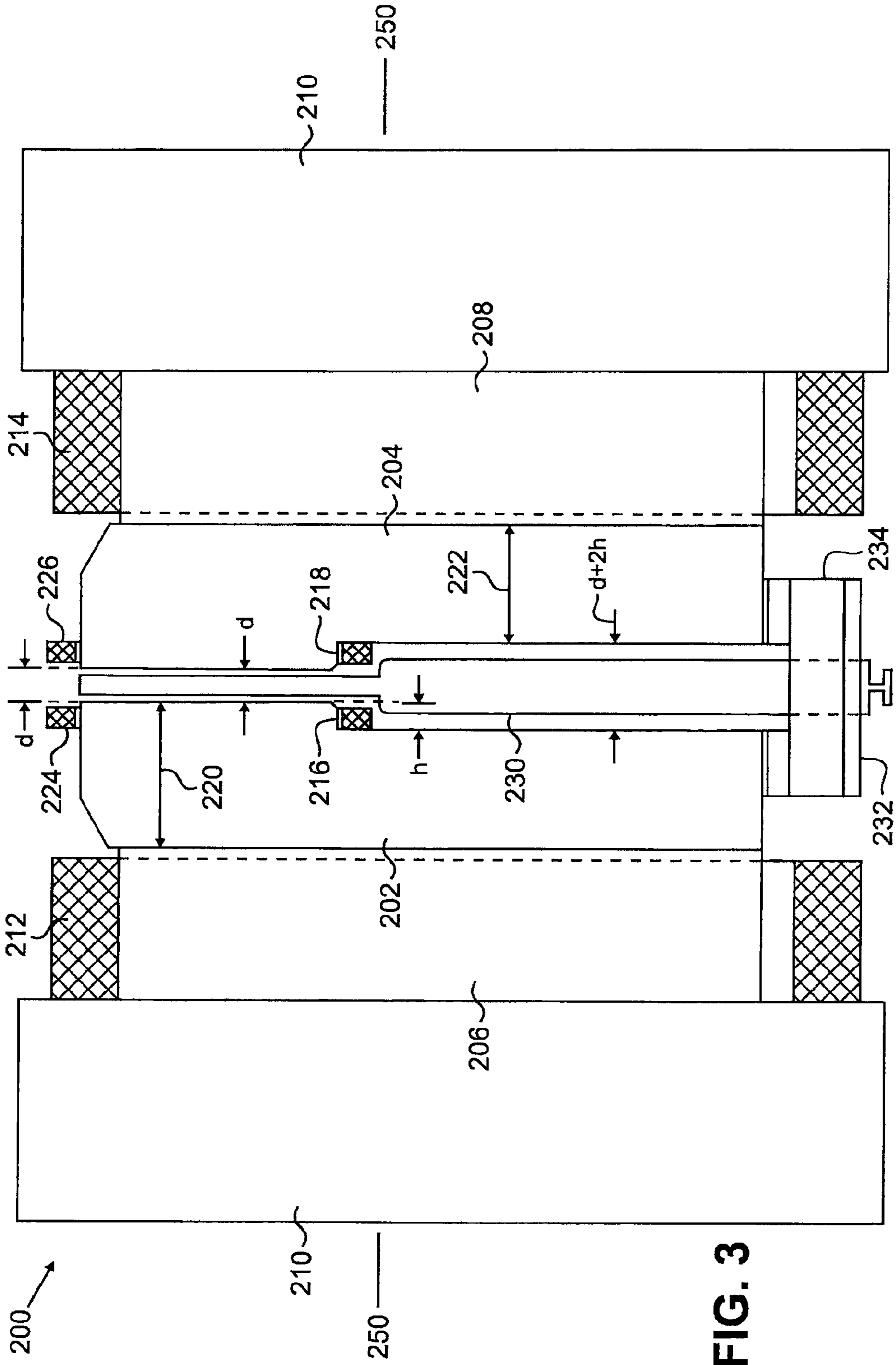


FIG. 2



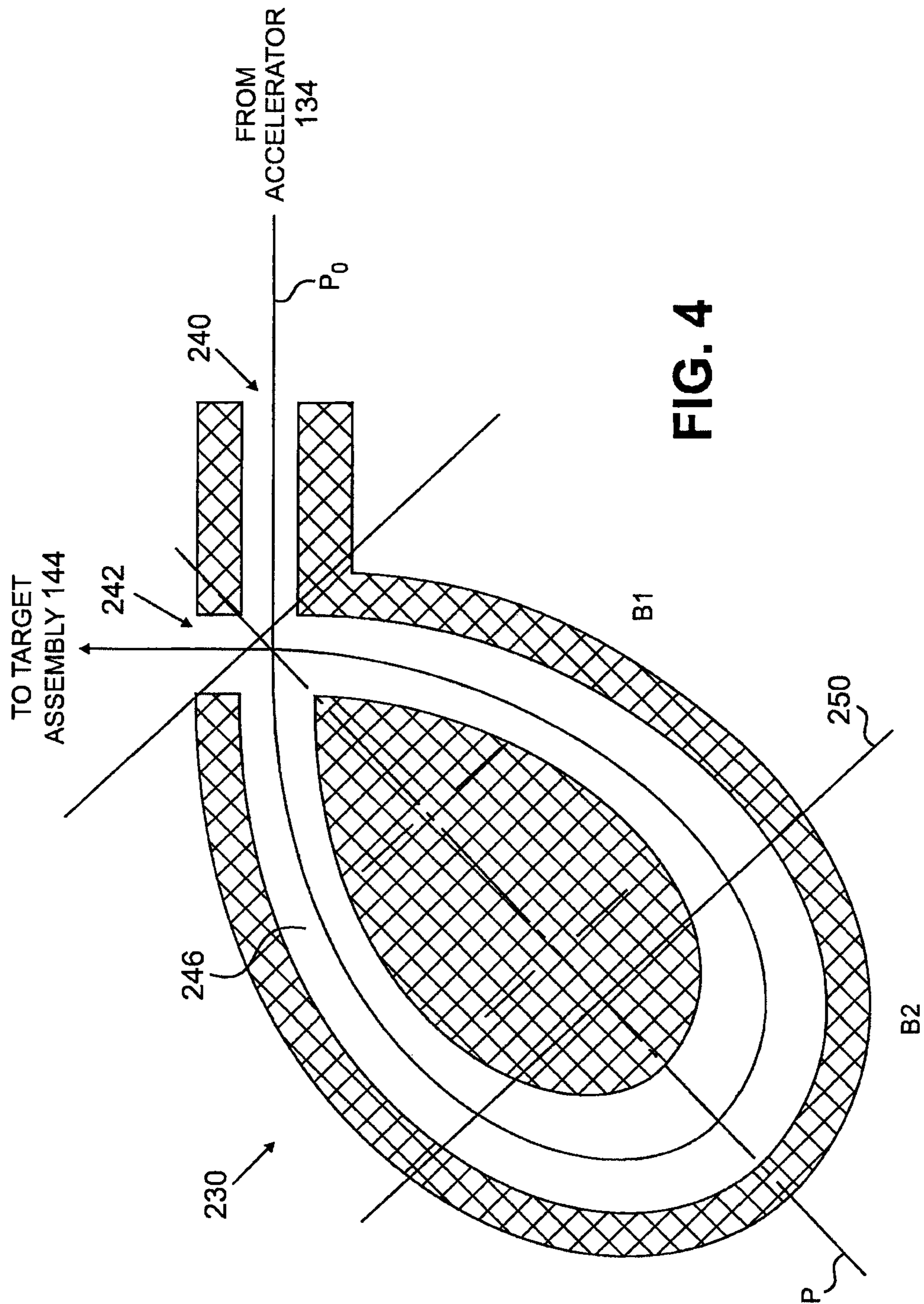


FIG. 4

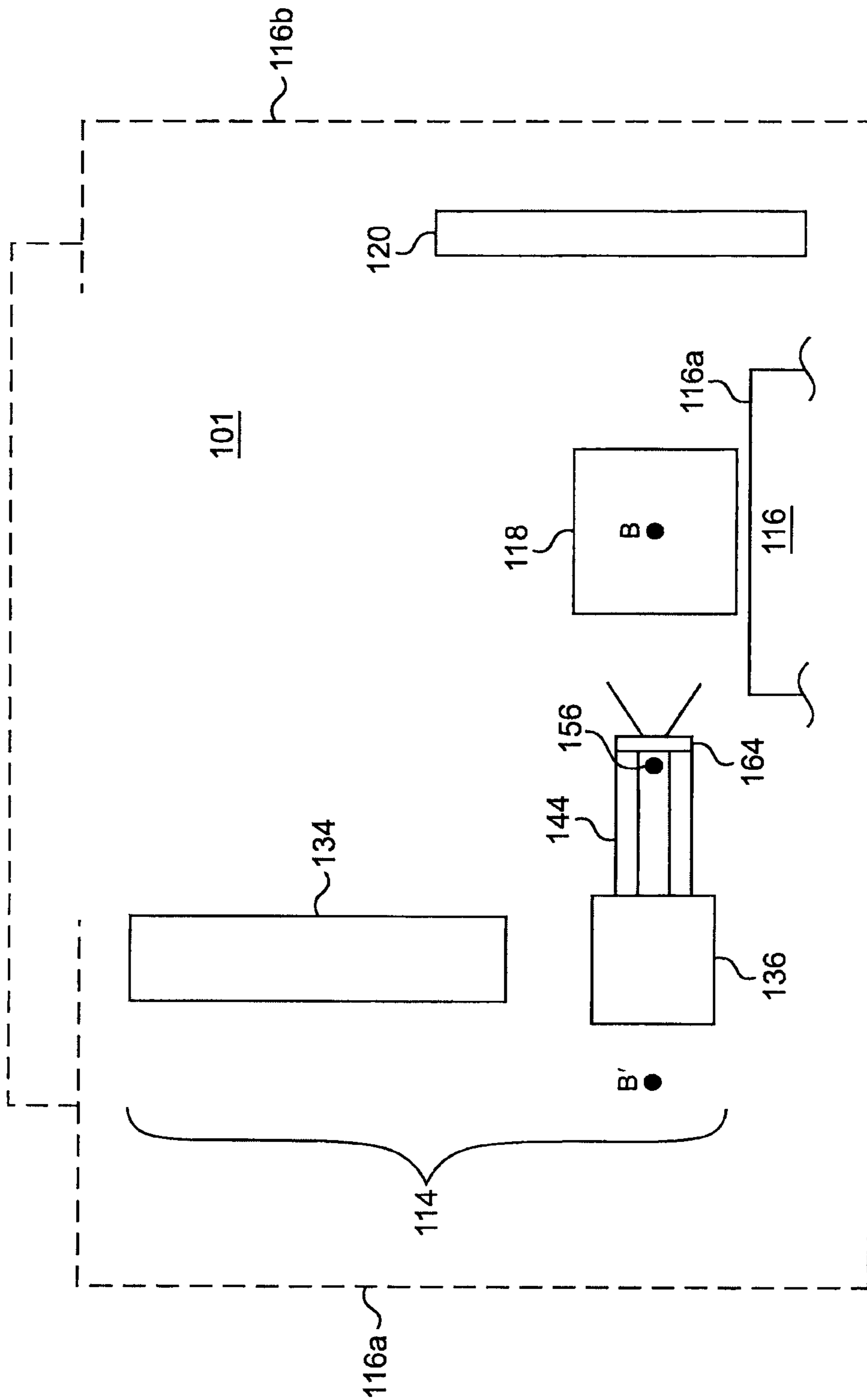


FIG. 5

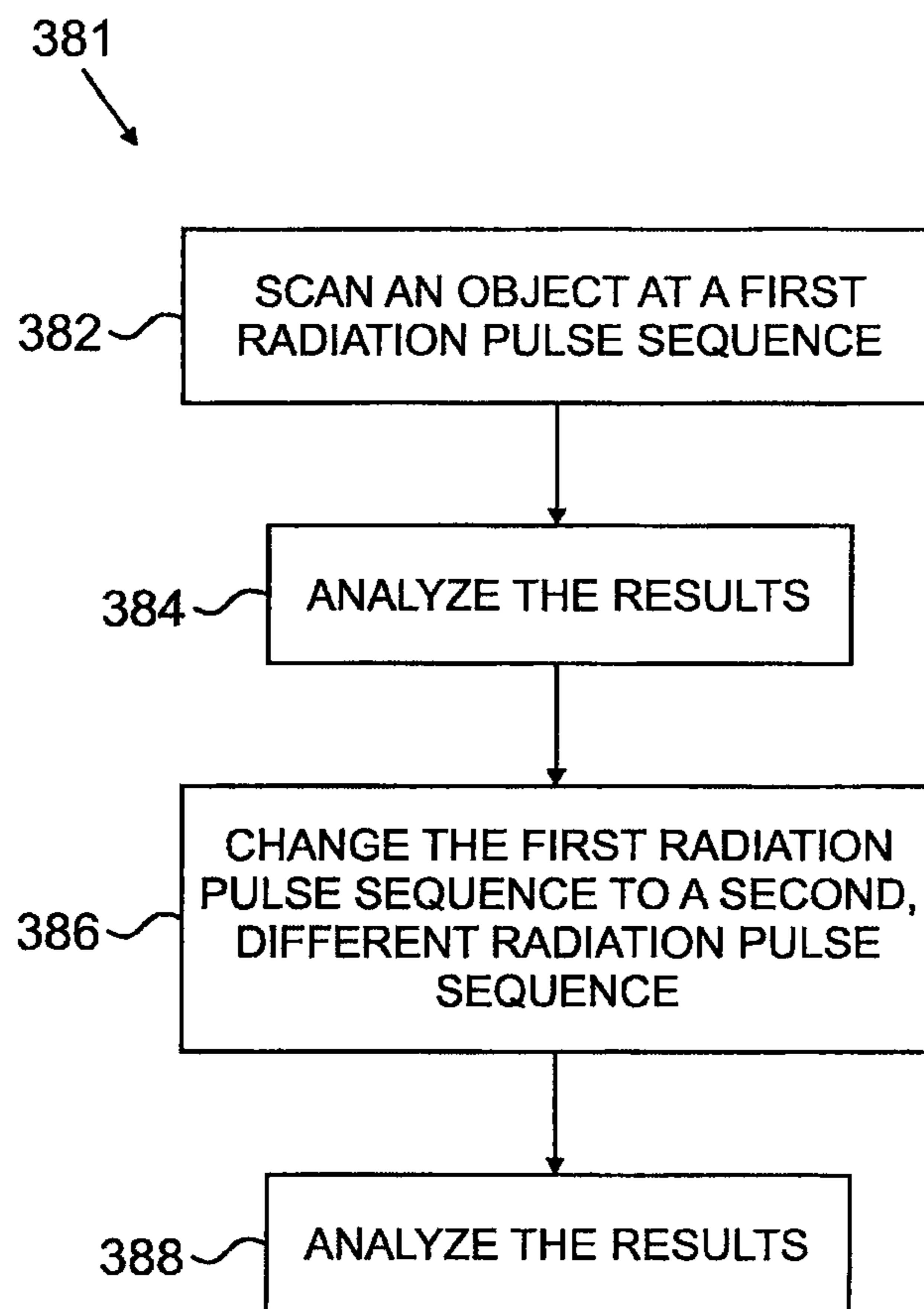


FIG. 6

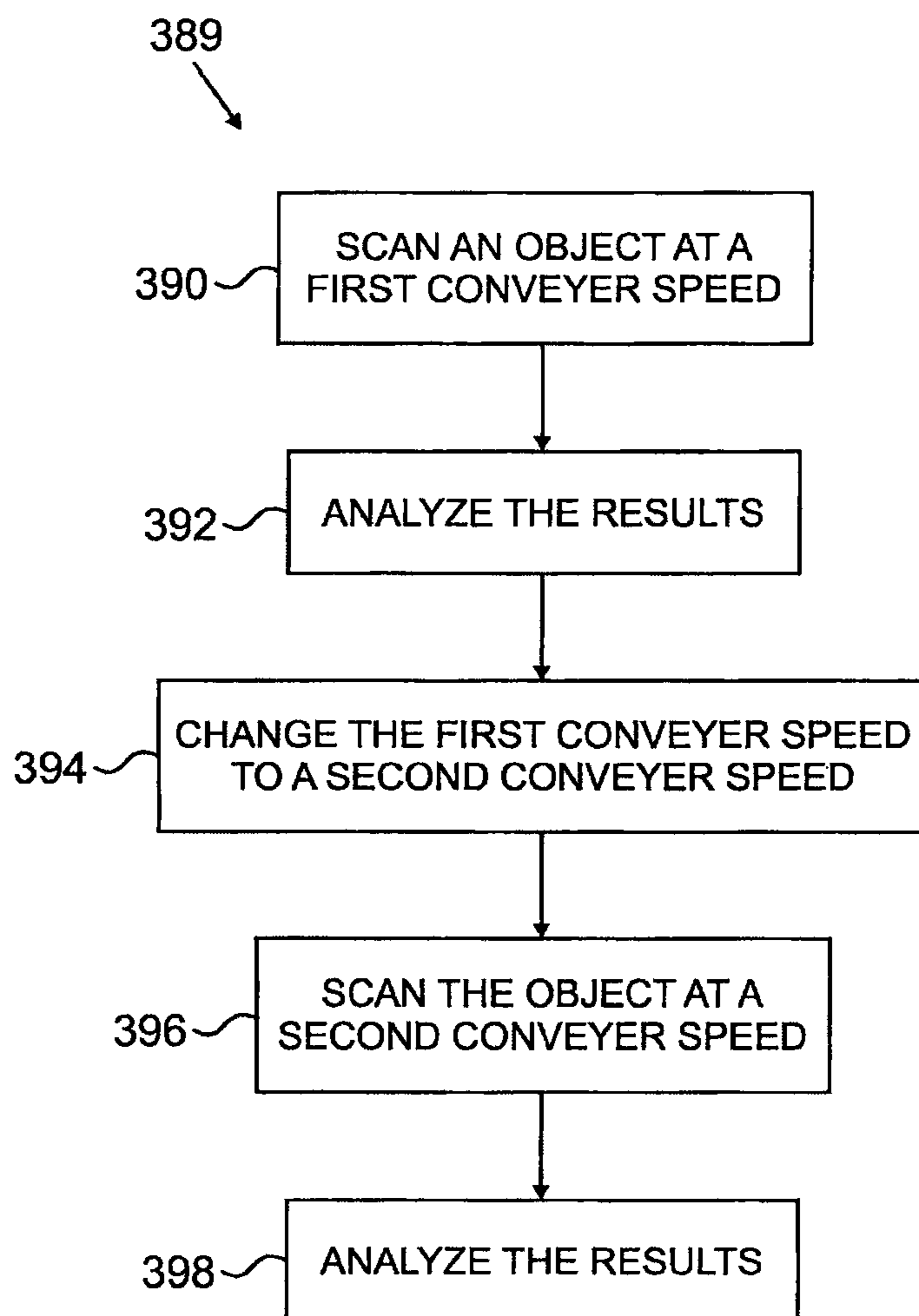


FIG. 7

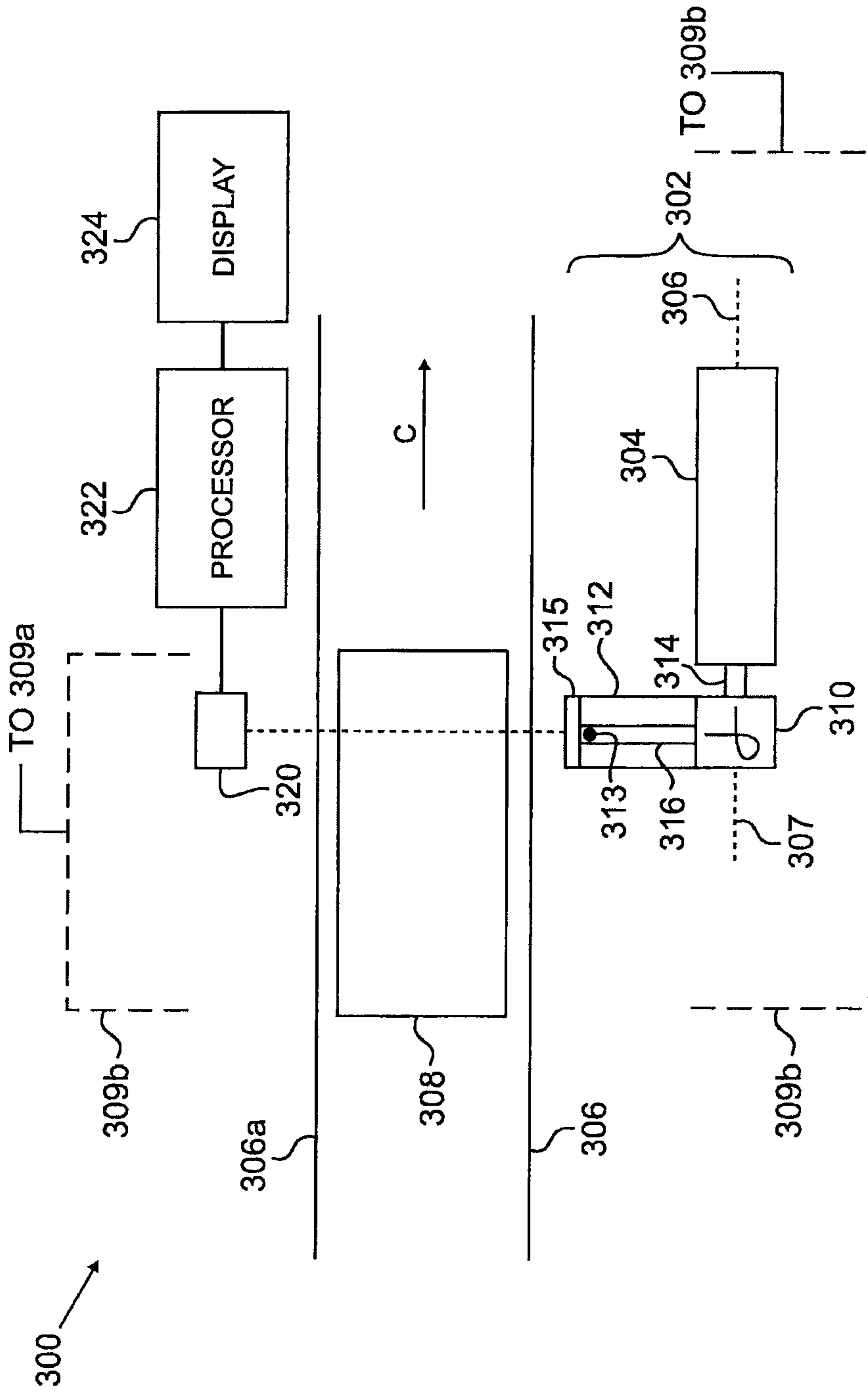


FIG. 8

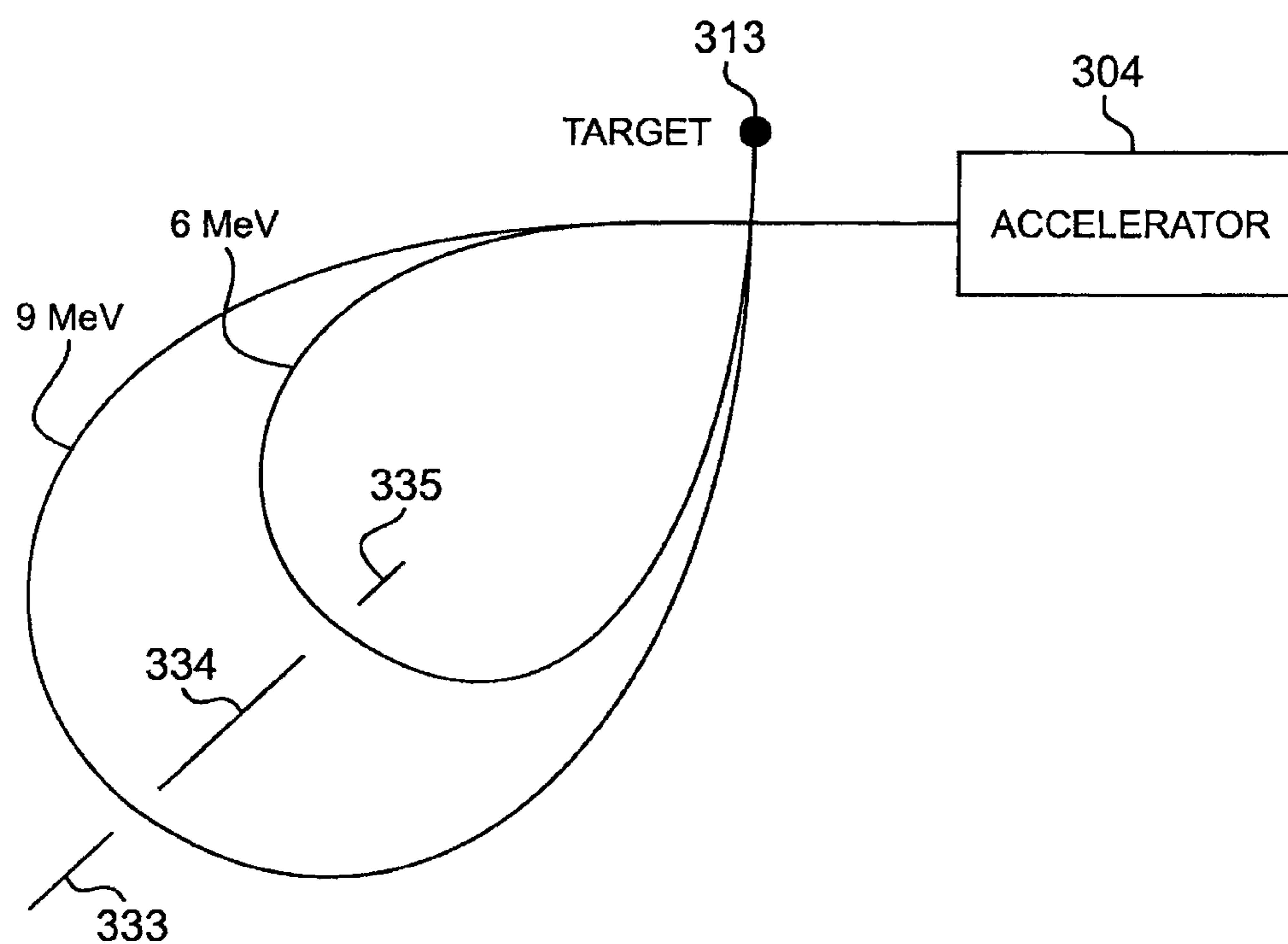


FIG. 9

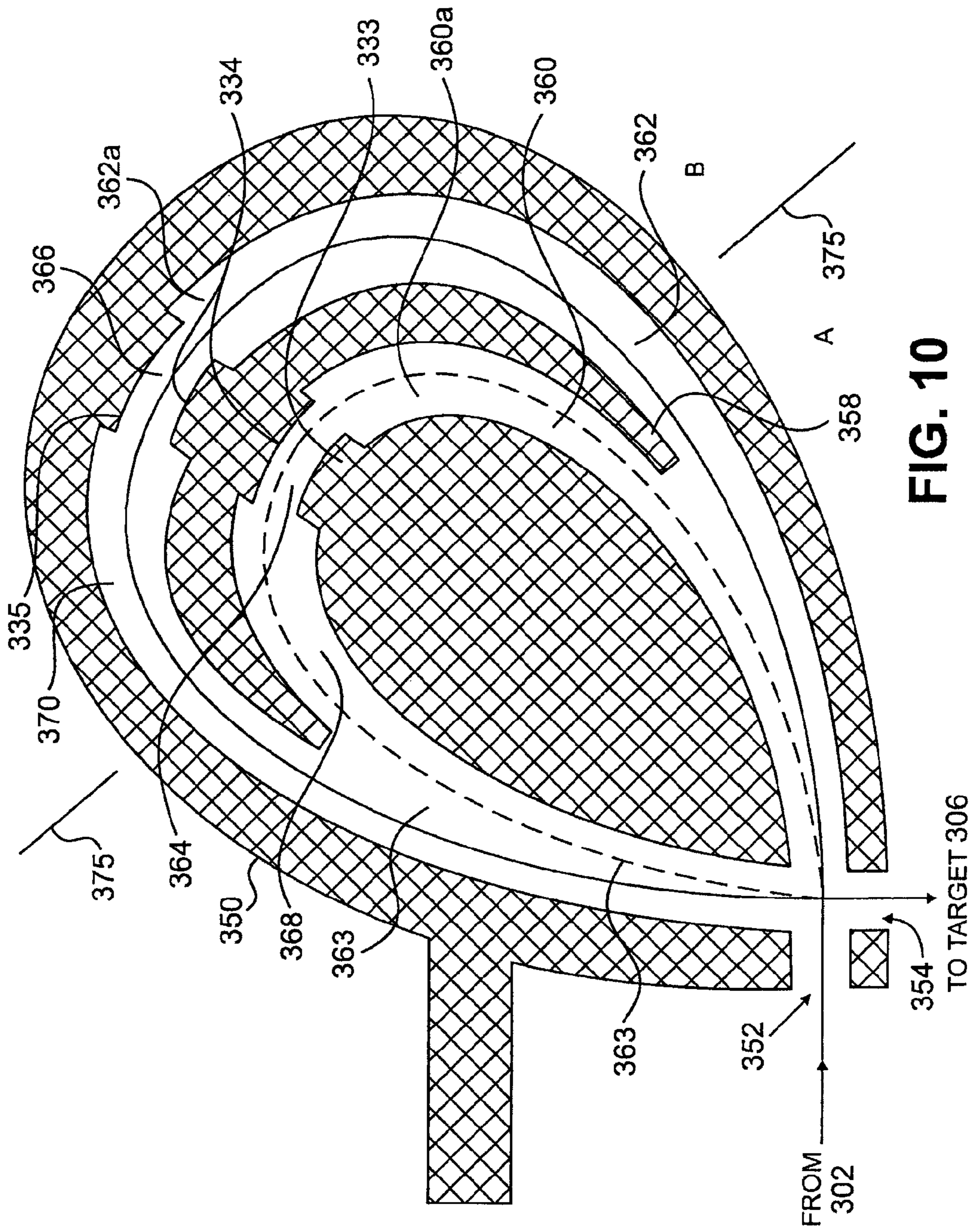


FIG. 10

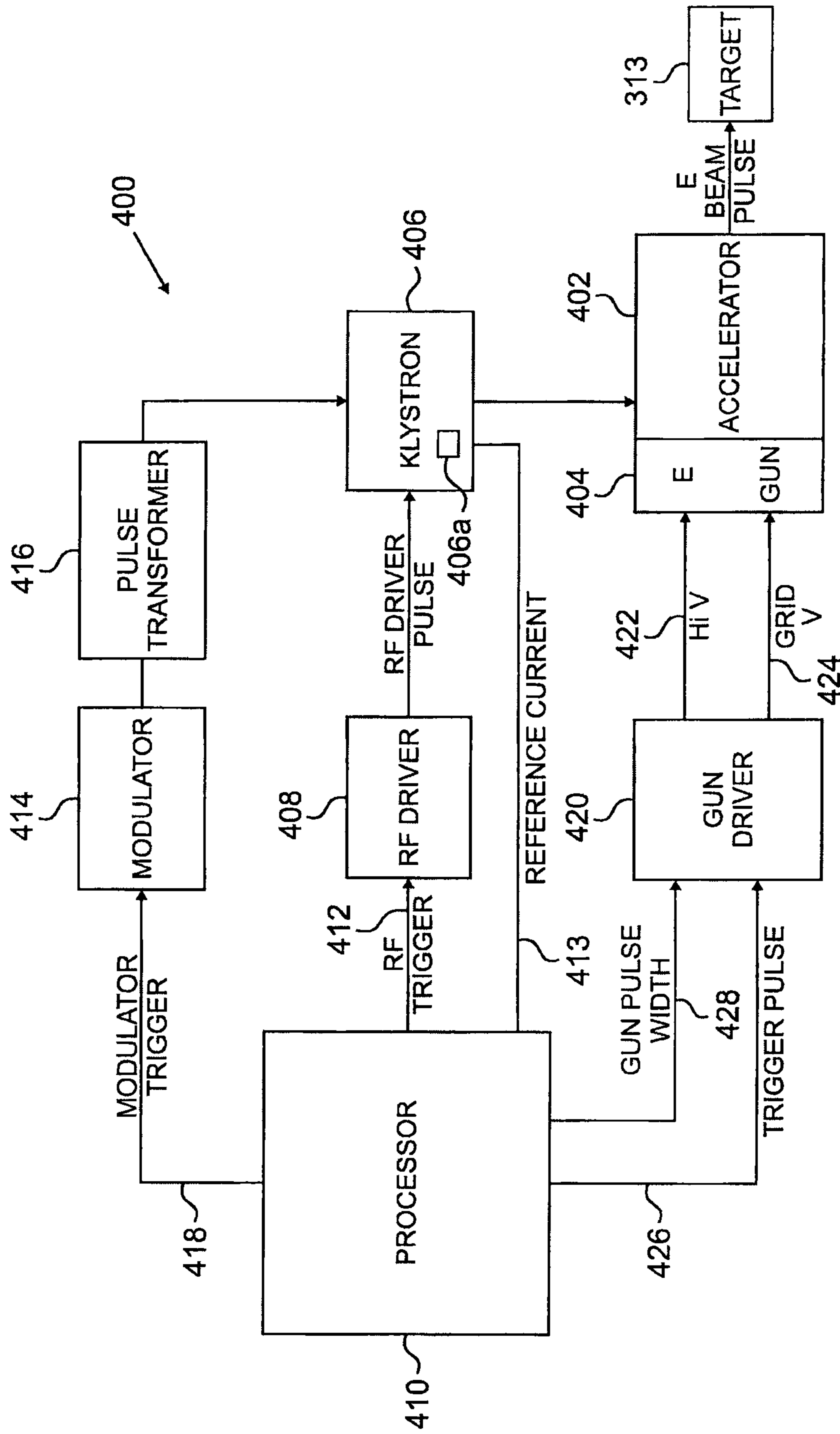


FIG. 11

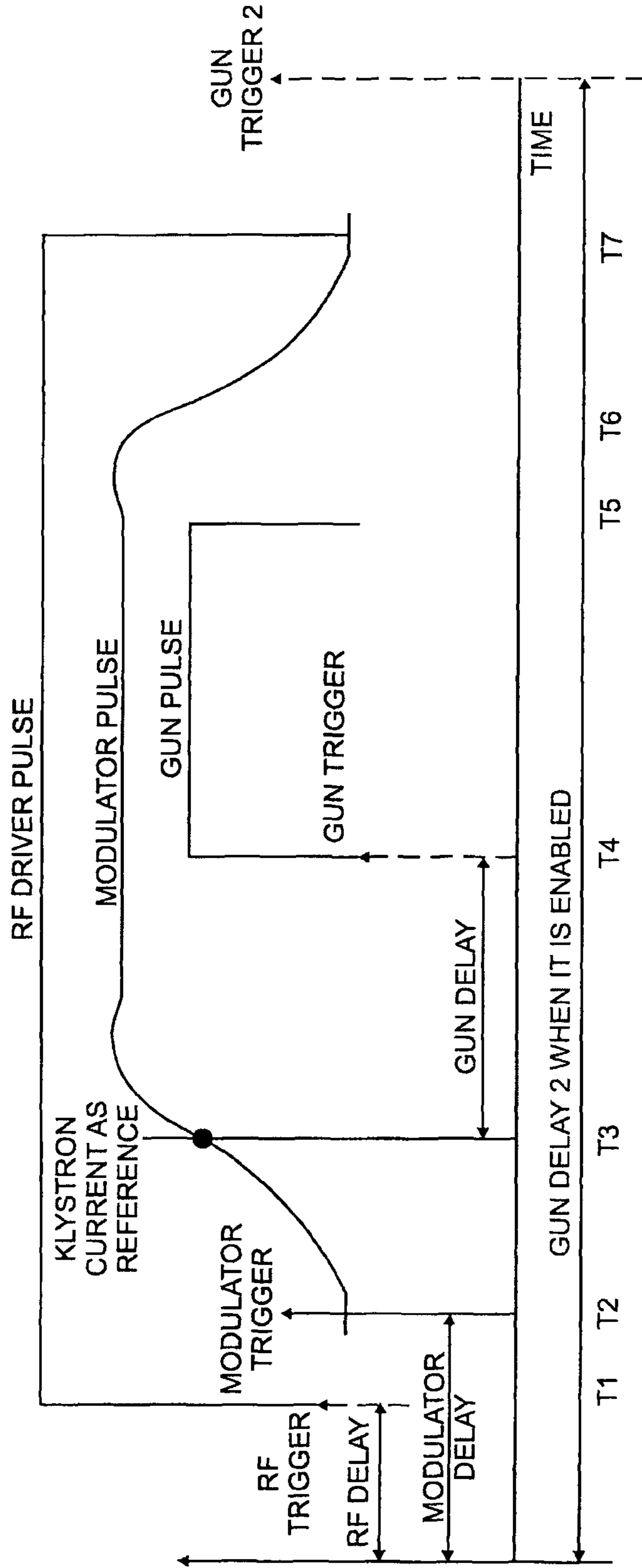


FIG. 12

COMPACT, INTERLEAVED RADIATION SOURCES

RELATED APPLICATION

The present application is a division of U.S. patent application Ser. No. 13/492,329, which was filed on Jun. 8, 2012 and will issue on Jul. 15, 2014 bearing U.S. Pat. No. 8,719,398, which is a division of U.S. patent application Ser. No. 12/313,752, which was filed on Nov. 24, 2008 and issued on Jun. 12, 2012 bearing U.S. Pat. No. 8,198,587, all of which are assigned to the assignee of the present invention, and are incorporated by reference herein.

FIELD OF THE INVENTION

Radiation sources and radiation scanning systems, and more particularly, X-ray radiation sources emitting radiation transverse to a longitudinal axis of the source and X-ray scanning systems using such sources for examining the contents of an object, for example.

BACKGROUND OF THE INVENTION

Radiation is commonly used in the non-invasive inspection of objects such as luggage, bags, briefcases, and the like, to identify hidden contraband at airports and public buildings. The contraband may include hidden guns, knives, explosive devices and illegal drugs, for example.

FIG. 1 is a front view of an example of an X-ray scanning system 10, referred to as a line scanner, for scanning luggage in airports, for example. The object 12 to be inspected is conveyed through a shielded tunnel 13 between a stationary source of radiation 14, such as X-ray radiation, and a stationary detector array 16, by a conveying system 18. The source 14 is typically a source of X-ray radiation of about 160 KeV to about 450 KeV. The source may be an X-ray tube, for example. The radiation is collimated into a fan beam 20 that intercepts the entire height of the object 12. Windows 21a, 21b are provided in the walls of the tunnel 13 to allow for the passage of radiation to the object 12 from the source 14 and from the object to the detector array 16. The detector array 16 may also be provided within the shielded tunnel 13, in which case only one window 21a would be required. The conveyor system 18 may comprise a mechanically driven belt comprising material that causes low attenuation of the radiation. The conveyor system 18 can also comprise mechanically driven rollers, with gaps in the rollers to allow for the passage of the radiation. Shielding walls 22 surround the source 14, the detector 16 and a portion of the conveying system 18. Openings (not shown) are provided in the shielding walls 22 for the object to be conveyed into and out of the scanning system 10 by the conveying system 18. Such systems are generally large. In another example, the object may be stationary and the radiation source and detector may be moved past the object by a suitable conveying system.

Radiation transmitted through the object 12 is attenuated to varying degrees by the object and its contents. The attenuation of the radiation is a function of the amount (thickness) and atomic composition of the materials through which the radiation beam passes. The attenuated radiation is detected and radiographic images of the contents of the object 12 are generated for inspection. The images show the shape, size and varying densities of the contents.

Standard cargo containers are typically 20-50 feet long (6.1-15.2 meters), 8 feet high (2.4 meters) and 6-9 feet wide

(1.8-2.7 meters). Air cargo containers, which are used to contain plural pieces of luggage or other objects to be stored in the body of an airplane, may range in size from about 35×21×21 inches (0.89×0.53×0.53 meters) up to about 240×96×118 inches (6.1×2.4×3.0 meters). Large collections of objects, such as many pieces of luggage, may also be supported on a pallet. Pallets, which may have supporting sidewalls, may be of comparable sizes as cargo containers. The term “cargo conveyance” is used herein to refer to both cargo containers and pallets. The low energies used in typical X-ray luggage and bag scanners, described above (160 KeV-450 KeV), are too low to penetrate through the much larger cargo containers or collections of objects. In addition, many such systems are too slow to economically inspect larger objects, such as cargo containers.

To penetrate larger cargo containers, X-ray radiation of at least about 1 MeV range is generally required. Linear accelerators may be used to generate X-ray radiation in the MeV range. The actual size may depend on the frequency band of the accelerator and the amount of shielding, which is dependent on the energy and flux of the generated radiation, as well as the expected locations of people and the amount of time those people may be exposed to radiation. Typical X-ray scanning system used to screen cargo containers have lengths ranging from about 1 meter to about 5 meters for 3-4 MeV system, and up to about 3.3 meters for a 5-15 MeV system. In addition, the intensity of the radiation is greatest in a forward direction, along the longitudinal axis of the electron beam. The uniformity of the emitted radiation decreases as the angle from the forward direction is increased. To maintain dose rate uniformity, at peak X-ray energy of about 9 MeV, for example, a narrow beam having a total arc of up to about 30 degrees tends to be used. At a peak energy of about 3 MeV, a beam having an arc up to about 65-70 degrees may be used. The smaller the arc, the farther the source must be in order to intercept the entire object. The length of the high energy X-ray sources and the beam arc tend to make higher energy X-ray scanning systems large. At these high energies, more shielding is also generally required.

It has been found to be difficult to distinguish nuclear devices and nuclear materials from other dense or thick items that may be contained within the object by standard X-ray scanning. The information that may be derived about the material type of the contents of objects by X-ray scanning may be enhanced by the use of radiation beams in the MeV energy range, with two or more different energy spectra that interact differently with the material contents of the object. For example, the attenuation of a 6 MeV X-ray radiation beam by the contents of the object will be different from the attenuation a 9 MeV X-ray radiation beam by the same contents, due to the differing effects of Compton Scattering and induced pair production on the different energy beams. A ratio of the attenuations at the two X-ray energies may be indicative of the atomic numbers of the material through which the radiation beam passes, as described in U.S. Pat. No. 5,524,133, for example, which is incorporated by reference herein. More sophisticated dual energy analysis techniques are described in U.S. Pat. No. 7,257,188, for example, which is assigned to the assignee of the present invention and incorporated by reference herein. Ratios of high and low energy attenuations may also be plotted against object thickness to facilitate material identification, as described in “Dual Energy X-ray radiography for automatic high-Z material detection,” G. Chen et al, NIM (B), Volume 261 (2007), pp. 356-359, which is also incorporated by reference herein.

SUMMARY OF THE INVENTION

Since the space occupied by an X-ray scanning system could often be used for other important purposes, a more compact X-ray scanning system would be advantageous.

In accordance with an embodiment of the invention, a radiation scanning system to examine contents of objects is disclosed comprising first and second radiation sources, each comprising first and second respective sources of charged particles coupled to first and second respective accelerators. The first and second accelerators each accelerate the first and second charged particles to a first and second energies, respectively. The radiation sources further comprise first and second respective targets. A first bend magnet is positioned to receive the accelerated first charged particles along a first axis from the first accelerator and to direct the charged particles toward the first target along a second axis different from the first axis. A second bend magnet is positioned to receive the second accelerated charged particles from the second accelerator along a third axis and to direct the charged particles toward the second target along a fourth axis different from the fourth axis. Impact of the first and second accelerated charged particles on the first and second targets, respectively, causes generation of radiation having first and second energies, respectively. At least one detector is positioned to detect radiation after interacting with the object. The system further comprises a support to support an object to be scanned. The support may be part of a conveyor system to move the object through the first and second radiation beams during scanning. The system may further comprise a conveyor system to move at least one of the at least one detector and the radiation sources past the object. In other words, the conveyor system may move the radiation sources and/or the at least one detector. The first and second radiation sources may be the same.

The first and second targets may be positioned on a first side of the conveyor system and the at least one detector may be positioned on a second side of the conveyor system opposite the first side. The at least one detector may comprise a first detector aligned with the first radiation source and a second detector different than the first detector, aligned with the second radiation source. The first radiation beam and the second radiation beams may comprise X rays. The charged particles may comprise electrons.

A processor may be coupled to the first and second radiation sources. The processor may be configured to selectively activate the first source or the second source to selectively cause generation of the first radiation beam from the first radiation source or the second radiation beam from the second radiation source. The processor may be configured to implement a first predetermined radiation pulse pattern and to change the first predetermined radiation pulse pattern to a second predetermined radiation pulse pattern different than the first radiation pulse pattern based, at least in part, on the radiation detected at least one of the energies during execution of the first predetermined radiation pulse pattern. The processor may also be configured to cause operation of the conveyor system at a first speed during scanning and change the first speed to a second, different speed during scanning, based, at least in part, on the radiation detected at least one of the energies while scanning at the first speed.

The first radiation beam and the second radiation beam may each have energies of at least 1 MeV. The first radiation beam may have an energy of 6 MeV and the second radiation beam may have an energy of 9 MeV.

The first and second bend magnets each comprise stepped-field bend magnets or Enge magnets, for example. The first and second bend magnets may be configured to bend the first and second charged particles 270°.

In accordance with another embodiment, a method of generating radiation is disclosed comprising accelerating first charged particles to a first energy, bending the first charged particles toward a first target, generating radiation having a second energy from impact of the first charged particles on the target, accelerating second charged particles to a third energy different than the first energy, bending the second charged particles toward a second target, and generating radiation having a fourth energy different from the second energy from impact of the second charged particles on the target.

The method may comprise accelerating the first and second charged particles by a single accelerator, bending the first and second accelerated charged particles toward the same target by a single magnet, and generating radiation having the second and fourth energies from impact of the first and second accelerated charged particle beams on the same target. The method may comprise accelerating the first and second charged particles by first and second, separate, accelerators, and bending the first and second charged particles by first and second, different magnet systems.

The first and second charged particles may be bent by 270 degrees. The first and second charged particles may be bent by a varying magnetic field, or the first and second charged particles may be bent by a first and second, different magnetic fields. The first and second charged particle beams may be bent around respective, different, radii through an orbit chamber defining at least partially separate passages through the orbit chamber, for each charged particle beam.

In accordance with another embodiment, a radiation scanning system to examine contents of objects is disclosed comprising a source of charged particles, a charged particle accelerator having an input coupled to the source of charged particles to receive the charged particles, and an output to allow accelerated charged particles to exit the accelerator along a first axis. The charged particle accelerator is configured to generate a first beam of accelerated charged particles having a first energy and a second beam of accelerated charged particles having a second energy different than the first energy. A target is positioned along a second axis different than the first axis and a magnet system is provided along the axis, configured to deflect the first and second accelerated charged particles along the second axis, toward the target. Impact of the first charged particle beam on the target causes generation of a first radiation beam having a first energy and impact of the second accelerated charged particle beam on the target causes generation of a second radiation beam having a second energy different than the first energy. A support is provided to support an object for scanning. A detector is provided to detect radiation after interacting with the object. The charged particle source may comprise a source of electrons and impact of the first and second charged particle beams on the target may cause generation of X-ray radiation. The support may be part of a conveyor system to move the object through the first and second radiation beams, during scanning. A conveyor system may be provided to move the source and the detector past the object during scanning.

The radiation source may be on a first side of the conveyor system and the detector may be on a second side of the conveyor system opposite to the first side, to detect radiation transmitted through the object. The first and second axes may be transverse and the magnet system may be configured

5

to deflect the first and second charged particle beams 270 degrees, from the first axis to the second axis.

The magnet system may further comprise an orbit chamber defining an inlet, an outlet, and a passage coupling the inlet to the outlet. The passage is configured to allow passage of the first accelerated charged particle beam and the second accelerated charged particle beam from the inlet to the outlet.

The orbit chamber may further define a wall in a portion of the passage separating a portion of the first passage from a portion of the second passage, to define separate partial passages for the first charged particle beam and the second charged particle beam. The wall may extend from a portion of the passage proximate the inlet to a portion of the passage proximate the outlet.

The orbit chamber may define a first, wider portion of each passage upstream of a second, narrower portion of each chamber. A wall transverse to the passages defines a step between the first and second portions.

In accordance with another embodiment of the invention, a method of conducting radiation scanning of an object is disclosed, comprising scanning an object with a first radiation beam pulse pattern comprising at least one of at least two different radiation beams each having a different characteristic, detecting the radiation, and analyzing the radiation detected during at the first pulse sequence. The method further comprises scanning the object with a second radiation beam pulse pattern, if suspect material is at least potentially identified, and analyzing the radiation detected during at the second pulse sequence.

Reference to the "energy" of a radiation beam refers to an energy characteristic of the radiation beam. The characteristic may be the nominal energy, average energy, or energy end point (peak energy) of the beam, for example. The term may encompass other characterizations of the energy of the beam, as well.

BRIEF DESCRIPTION OF THE FIGURES

FIG. 1 is a front view of an example of a prior art X-ray scanning system, referred to as a line scanner, for scanning luggage in airports;

FIG. 2 is a schematic representation of a top view of a dual energy radiation scanning system in accordance with an embodiment of the invention, comprising first and second radiation sources;

FIG. 3 shows a pole piece of an example of an electromagnet, which may be used in a bend magnet system in embodiments of the present invention;

FIG. 4 is a schematic diagram of a cross-section of an example orbit chamber that may be used in the bend magnet systems in the embodiment of FIG. 1;

FIG. 5 is a schematic diagram of another example of the embodiment of FIG. 1, in which the accelerators are vertical;

FIG. 6 is an example of a method for changing radiation pulse sequences, in accordance with an embodiment of the invention;

FIG. 7 is an example of a method for changing conveyor speed, in accordance with another embodiment of the invention;

FIG. 8 is a schematic representation of another example of a dual energy radiation scanning system in accordance with an embodiment of the invention, comprising one accelerator;

FIG. 9 is a schematic representation of two beam paths, one for a low energy accelerated electron beam and the other

6

for a high energy accelerated electron beam, turned 270 degrees by the bend magnet system, in the embodiment of FIG. 8;

FIG. 10 is a cross section of an example of an orbit chamber that may be used with the high and low energy accelerated electron beams of FIG. 9;

FIG. 11 is a schematic representation of an example of a radiation source that may be switched between accelerating charged particles, such as electrons, to different energies; and

FIG. 12 is an example of a timing diagram for the radiation source of FIG. 11.

DETAILED DESCRIPTION OF PREFERRED EMBODIMENTS

FIG. 2 is a schematic representation of a top view of a dual energy radiation scanning system 100 in accordance with an embodiment of the invention, comprising a first radiation source 112 and a second radiation source 114, adjacent to a support 116 for the object 118. In this example, the support 116 is a conveyor that moves the object 118, such as a cargo conveyance, in a direction A along an axis 130, past the radiation sources 112, 114. The conveyor 116 includes a flat surface 117 that supports the cargo conveyance 118. The radiation sources 112, 114 may be configured to generate fan beams or cone beams, for example, through which the object 118 is moved. Detectors 120, 122 are provided on an opposite side of the conveyor 116 than the radiation sources 112, 114. The detectors 120, 122 are aligned with the sources 112, 114, to detect radiation passing through the cargo conveyance 118. The detectors 120, 122 are coupled to a processor 124 and a display 126. The processor 124, or another processor, may be coupled to the radiation sources 112, 114, and to the conveyor 116a, 116b, 116c to control their operation, as well. The detectors 120, 122 may be detector arrays, for example. Additional circuitry, such as analog-to-digital circuitry, may be provided between the detectors 120, 122 and the processor 124, as is known in the art.

In an alternative configuration, the support 116 is a platform, the radiation sources 112, 114 are supported by a conveyor 116 (indicated in phantom in FIG. 2), and the detectors 120, 122 are supported by another (or the same) conveyor system 116b, also shown in phantom. The conveyors 116a, 116b move the radiation sources 112, 114 and the detectors 120, 122 past the stationary object 118 in the direction A'. The radiation beams emitted by the sources 112, 114 toward the object 118 are then moved through the object. Conveying systems that move a radiation source and/or a detector past a container during scanning are known in the art. A straddle type system for moving both a source and a detector past a container is described in U.S. Pat. No. 5,638,420, which is incorporated by reference herein.

In this example, the radiation sources 112, 114 are linear accelerators arranged horizontally, with their longitudinal axes parallel to an axis 130 of the conveyer system 116, to provide a more compact system than if the linear accelerators were perpendicular to the direction of movement of the conveying system 116 or the conveying systems 116a, 116b, as in the system 10 of FIG. 1. The longitudinal axes of each linear accelerator may be aligned with the same axis 128 or different axes parallel to the axis 130. Instead of being parallel to the directions of movement A, A', the long axes of the linear accelerators may also be transverse to the directions of movement, but not perpendicular to the directions of movement A, A', to provide a more compact system

than if the accelerators were perpendicular, even if not as compact as the configuration of FIG. 2.

The first and second linear accelerators **112**, **114** each comprise a respective accelerator **132**, **134**, to accelerate charged particles, such as electrons, to different nominal energies, as is known in the art. The charged particles are provided by charged particle sources **133**, **135**, such as electron guns, for example.

The accelerated charged particles output from each of the accelerators **132**, **134** may be coupled to bend magnet systems **136**, **137** through drift tubes **138**, **140**, respectively. The accelerators **132**, **134**, bend magnet systems **136**, **137**, and drift tubes **138**, **140** are under vacuum, as is known in the art. Drift tubes **150**, **152** are provided at the output of the bend magnet systems **136**, **137**, to couple the bend magnet systems to target assemblies **142**, **144**, and to the targets **154**, **156**, respectively. The drift tubes **150**, **152** and the target assemblies **142**, **144** are also under vacuum.

The target assemblies **142**, **144** comprise targets **154**, **156**, such as tungsten, for example, as is known in the art. Shielding material **158**, **160** surrounds the drift tubes **150**, **152** and targets **154**, **156**. Collimators **162**, **164** may be provided downstream of each target assembly **142**, **144**, respectively, to shape the radiation beam emitted by the targets **154**, **156**. Each radiation beam may be collimated into a fan beam or a cone beam, for example.

The radiation sources **112**, **114** may be sources of X-ray radiation, for example. The nominal electron energies of the radiation sources **12**, **14** may be 9 MeV and 6 MeV respectively, for generating X-ray beams having energies of 9 MV and 6 MV, respectively. 9 MV and 6 MV X-ray radiation beams are appropriate for scanning cargo conveyances, such as cargo containers having a thickness of 6 feet (1.8 m) or more, for example. Other nominal electron energies for generating other X-ray energies, to scan cargo conveyances or for other applications, may be provided. For example, nominal electron energies of the radiation sources **112**, **114** may be 6 MeV and 1 MeV, to generate nominal X-ray energies of 6 MeV and 1 MeV, or 6 MeV and 3.5 MeV, may be provided to generate X-ray energies of 6 MeV and 3.5 MeV, respectively. The dose rate of the two radiation sources in this example are the comparable.

The linear accelerators **132**, **134** may each be a LINAC-TRON® or CLINAC® available from Varian Medical Systems, Inc., Palo Alto, Calif., for example. The sources may emit pulses of charged particles, such as 360 pulses per second, or more, for example. In the Varian Linatron®, up to 500 pulses are output per second. Linear accelerators that may be used are also described in U.S. Pat. No. 6,864,633 B2, and 6,366,021 B1, which are assigned to the assignee of the present invention and are incorporated by reference herein.

The bend magnet systems **136**, **137** may be 270° bending magnet systems **134**, **136**, for example. The bend magnet systems **136**, **137** bend the charged particles received from the first linear accelerator **112** and the second linear accelerator **114** toward the targets **142**, **144**, respectively. Impact of the charged particles on the targets **142**, **144** generates X-ray radiation due to the Bremsstrahlung effect, as it is known in the art. The beam of charged particles is turned 90 degrees from the axis of the accelerator, toward the target, by deflecting the beam 270 degrees by one or more magnetic fields, as is known in the art. Examples of bend magnet systems **136**, **137** that may be used are described in more detail below.

In one example, the bend magnet systems **136**, **137** each comprise a 270° stepped field bending magnet which is at

least approximately achromatic so that it causes only a small dispersion of the charged particle beam at an output of the magnet, as is known in the art. An example of a stepped field magnet is described in U.S. Pat. No. 4,425,506 (the '506 patent), which is incorporated by reference herein. In the '506 patent, a stepped magnet subjects charged particles to at least two adjacent regions, each with a different, homogeneous magnetic field, while traversing one-half of a symmetric trajectory. The beam of charged particles is first subjected to a low magnetic field in a low magnetic field region, which causes the beam to bend around a first angle α_1 , then it enters a high magnetic field in a high magnetic field region, where it is deflected through a second angle $2\alpha_2$ (α_2 on each side of a symmetry plane). The beam then re-enters the low magnetic field region, where it is deflected another angle α_1 , for a total bend of 270° ($2(\alpha_1+\alpha_2)$).

The ratio of the high magnetic field to low magnetic field may be about three-to-one, for example. All the pole faces are parallel, which creates intrinsic symmetries in the optical properties and facilitates manufacture.

FIG. 3 shows a pole piece **200** of an electromagnet described in the '506 patent, which may be used in embodiments of the present invention. The pole piece **200** comprises pole caps **202**, **204**, which are coupled to outer poles **206**, **208** of the magnet. The outer poles **206**, **208** are coupled to a yoke **210**. Current carrying coils **212**, **214** are disposed about respective outer poles **206**, **208**, to cause generation of the magnetic field. Steps **216**, **218** divide the pole caps **202**, **204** into a thicker region **220** and a thinner region **222**. The thicker region **220** defines a narrower gap (d) and the thinner region **222** defines a wider gap ($d+2h$) between the pole caps **202**, **204**. The thinner region **222** defines a first, uniform, lower, magnetic field B_1 on one side of a plane **250** and the thicker region **220** defines a second, uniform, higher magnetic field B_2 on the other side of the plane **250**. Trim coils **224**, **226** provide a vernier to adjust the ratio between the high and low magnetic fields.

A vacuum envelope **230**, which is a thin-walled metal vessel that defines a path for charged particles to follow as the charged particles are curved by the magnetic field, is provided between the pole caps **202**, **204** of the magnet **200**, partially positioned within the thicker region **220** and thinner region **222** of the pole caps. The vacuum envelope **230**, also referred to as an orbit chamber in the art, is under vacuum.

FIG. 4 is a schematic diagram of a cross-section of an example orbit chamber **230** that may be used in each bend magnet. The orbit chamber **230** has an inlet **240** along a first axis, an outlet **242** along a second axis perpendicular to the first axis, and a passage **246** following a curved path turning 270° to connect the inlet **240** to the outlet **242**. The orbit chamber **230** may comprise oxygen-free electronic grade copper, for example, as is known in the art. The passage **246** is defined in the copper.

The passage **246** may comprise a first, narrower portion (not shown) extending from the inlet **240** to a narrow choke or "energy slit," and a second, wider portion (not shown) extending from the choke to the outlet **242**, to intercept charged particles and remove charged particles at the periphery of the beam that have been dispersed by the magnetic field. An example of a choke is shown in FIG. 8.

The orbit chamber **230** is positioned between the pole caps **202**, **204** of the pole piece **200**, so that a portion of the orbit chamber is within the low magnetic field region B_1 defined by the thinner portion **222**, and a portion of the chamber is positioned within the higher magnetic field B_2 defined by the thicker portion **220**. The passage **246** is perpendicular to the magnetic field, as is known in the art.

Line **250** in FIG. **4** corresponds to the plane **250** in FIG. **3**, between the low magnetic field region **B1** and the high magnetic field region **B2**. A symmetry plane **P** of the orbit chamber **230** is indicated.

The entrances and exits of the orbit chambers **230** in the respective bend magnet systems **136**, **137** are coupled to the respective drift tubes **138**, **140**, **150**, **152**, which are also under vacuum, as mentioned above.

A field clamp **232** disposed from the pole caps **202**, **204** by an aluminum spacer **234** controls the fringing field at an entrance to and from the orbit chamber **230**.

Ellipticity of the electron beam is generally small. However, a quadrupole (not shown) may be provided to shape the electron beam to avoid ellipticity, if desired, as is known in the art. It is noted that in cargo scanning with a fan beam or a cone beam, ellipticity may not be a concern.

Another example of an approximately achromatic beam deflection system is described in U.S. Pat. No. 3,867,635 and 4,322,622, which are also incorporated by reference herein.

The beam of charged particles may be deflected by a continuously spatially varying magnetic field, as well, as described, for example, in Enge, Harold A., "Achromatic Magnetic Mirror for Ion Beams," *The Review of Scientific Instruments*, Vol. 34, No. 4, pp. 385-390, April 1963, for example, and in U.S. Pat. No. 3,379,911 ("the '911 patent"), which are also incorporated by reference herein. In these examples, the beam enters the magnet through a pole face with an adjustable angle. For nearly the first 135° the field is homogeneous. Then the beam passes through a short region where the field has a gradient in which the magnetic field increases in intensity as a function of radius from the center. The beam then re-enters the homogeneous field and exits through another pole face with an adjustable angle. Except for the input and exit pole face angles, the system is symmetric about a 45° diagonal line through the magnet. The gradient region enables achromaticity with respect to both position and angle as long as the magnet gap is small compared to the bend radius, and the target is sufficiently distant from where the beam exits the magnet.

In another example of a radiation scanning system **101** in accordance with an embodiment of the invention, the linear accelerators **132**, **134** adjacent to the conveyor system **116** are vertical, and perpendicular to the direction of movement of the object **118**, as shown in a side view of FIG. **5**, where the object **118** is moved in a direction **B** out of the page by the conveyor **16** (or the radiation sources and detectors may be moved in a direction **B'** out of the page. A surface **116a** of the conveyor **116** is perpendicular to the page and to the long axes of the accelerators **132**, **134**. Only the radiation source **114** is shown in this view. The linear accelerator **132** and the radiation source **112** are behind the radiation source **114** in this view and are not shown. One accelerator may be perpendicular to the direction of movement of the object **118** and one may be parallel, as well.

The processor **124** may be a logic circuit, such as an application-specific integrated circuit ("ASIC") or field programmable gate array ("FPGA"), a programmable logic controller, or a microprocessor, for example. In the systems **100**, **101** of FIGS. **2** and **4**, the processor **124** controls the operation of the radiation sources **112**, **114** so that they generate and emit radiation pulses in a desired pattern. In one example, the pattern may comprise an alternating pattern comprising one high energy radiation pulse (9 MeV, for example) followed by one low energy radiation beam (6 MeV, for example). In another example, two high radiation pulses may be followed by two low radiation pulses fol-

lowed by two high radiation pulses, etc. The pattern may also comprise different patterns of high and low radiation pulses, such as a repeating pattern of three high energy radiation pulses followed by one low energy pulse. Any pattern of radiation pulses may be generated. The detectors **120**, **122** may be enabled in a corresponding pattern to detect the emitted radiation after interaction with the object **118**.

The klystron **406** may be a 5.5 MW or a 3 MW S-band klystron from Communications and Power Industries, Inc., Palo Alto, Calif., for example. The rf driver **408** may be provided by Comtech PST Corp., Melville, N.Y., for example.

The accelerator **402** may be a standard S-band accelerator, such as the HE Energy CLINAC™, available from Varian Medical Systems, Inc., Palo Alto, Calif., which may be operated at either one of two energies by setting of an energy switch. The switch may be set to one of the higher or lower energies to be in optimum configuration for one of the energy settings during the interleaved operation, but not the other, or the switch may be set for an energy between the two desired energies. For example, the CLINAC™, may be set to operate at either 9 MV, 6 MV, or 7.5 MV to provide interleaved, pulsed radiation generation at 9 MeV and 6 MeV. An S-band accelerator operates in the frequency range of 2.4 GHz to 3 GHz. The accelerator **402** may also be an L-band, C-band, X-band, or K-band accelerator, instead, for example, which operate over different energy and frequency ranges. The frequency band of the klystron **406** should match the frequency band of the accelerator **402**.

During operation, as the object **118** is scanned by the alternating pattern of radiation pulses from the first and second radiation sources **112**, **114**, the detected radiation is processed by the processor **124** for display on the display **126**. Images may be displayed based on the data collected from each detector **120**, **122**, at each respective energy, and/or the data collected from each detector may be processed with each other and displayed. For example, dual energy images may be fused and displayed, for example.

In another example, ratios of the attenuations at the two X-ray energies, which may be indicative of the atomic numbers of the material through which the radiation beam passes, are calculated and analyzed. Ratios may be compared to tables correlating ratios with atomic numbers, as described in U.S. Pat. No. 5,524,133, for example, which is incorporated by reference herein. More sophisticated analysis of ratios from dual energy scanning may be used, such as those described in U.S. Pat. No. 7,257,188, for example, which is assigned to the assignee of the present invention and incorporated by reference herein. Ratios of high and low energy attenuations may also be plotted against object thickness to facilitate material identification, as described in "Dual Energy X-ray radiography for automatic high-Z material detection," G. Chen et al, *NIM (B)*, Volume 261 (2007), pp. 356-359, which is also incorporated by reference herein.

In this example, the interleaving of the high and low beams at high pulse repetition frequencies of, for example, from about 500 Hz to about 2000 Hz, enables capture of two images of nearly the same object view or slice, even when the object **118** (or the radiation sources **112**, **114**/detector **120**, **122**) is moving rapidly. Comparable dose output from the two sources **112**, **114** insures that both images are of comparable quality and capable of fusion for purposes of discrimination of objects of interest, such as Special Nuclear Materials.

The radiation pulse pattern can also be controlled in real time or nearly in real time based on inputs from previous frames. The processor **124**, or another processor, may ana-

lyze images and/or data in real time or substantially real time via computerized algorithms, such as those described in U.S. Pat. No. 7,257,188, for example, which is assigned to the assignee of the present invention and incorporated by reference herein. If a suspect material, such as Special Nuclear Material or high density material is at least potentially identified, the pulse pattern may be changed. Computerized algorithms may analyze the probability of a certain shape having been encountered in a previous frame, and change the pulse pattern if a potentially suspect item is identified, as well.

In one example, the processor **124**, or other such processor, may change the alternating radiation pulse pattern of high and low energy radiation beams from the first and second radiation sources **112**, **114** to all high energy radiation beams from only the high energy radiation source (source **114**, for example), if suspect material is at least potentially identified. When scanning of the suspect region is completed at the high energy, the original, alternating radiation pulse sequence, or another radiation pulse sequence, may be initiated by the processor. In another example, if analysis reveals the potential presence of a low density contraband, the processor **124** may change the alternating radiation pulse pattern to a pattern comprising only the low energy radiation pulses (6 MeV or 1 MeV, for example), from the low energy radiation source **112**, for example.

If suspected Special Nuclear Material is present, a neutron detection system may be activated by the processor **124** and the presence of delayed neutrons checked for after the high energy radiation pulses, as is also described in U.S. Pat. No. 7,257,188, which is assigned to the assignee of the present invention and incorporated by reference herein.

Another radiation source (not shown) may be activated for further testing, as well. For example, a radiation source may be positioned orthogonal to the direction of the radiation beams emitted by the first and second radiation sources, and activated for further testing of a suspect region based, at least in part, on the detected radiation. A “dual view” imaging system including orthogonal radiation sources is described in U.S. Pat. No. 8,137,976, which was filed on Jul. 12, 2006, is assigned to the assignee of the present invention and is incorporated by reference herein.

In another example, if analysis reveals the potential presence of Special Nuclear Material, another, higher energy radiation source (not shown) may be activated to generate pulses of higher energy radiation, such as 15 MeV, to detect delayed neutrons or for other analysis to better determine whether Special Nuclear Material may be present.

The radiation pulse pattern need not be alternating. In another example, only one of the radiation sources, either the high radiation source **114** or the low radiation source **112** may be caused to generate radiation pulses by the processor **124**, and if suspect material is identified, then the processor may implement an alternating pattern of high and low radiation pulses by activating both the low radiation sources **112** and the high radiation source **114** to generate radiation pulses for dual energy analysis, such as analysis of ratios, or only the high energy radiation source may be activated for a series of pulses.

Other parameters of the imaging scan may be changed automatically and in real time or nearly real time, based on the analysis of the detected radiation, as well. For example, the speed of the conveyor **116**, **116a**, **116b** may be decreased if suspect material is potentially identified, to increase the resolution of the analysis. The conveyor **116**, **116a**, **116b**

may also be reversed to check a suspect region of the object again, optionally in accordance with another radiation pulse pattern.

FIG. **6** is an example of a method **381** for changing radiation pulse sequences, in accordance with an embodiment of the invention. Scanning is conducted at a first radiation pulse pattern, in step **380**. The detected radiation is analyzed, in step **382**. The first radiation pulse pattern is changed to a second radiation pulse pattern based, at least in part, on the analysis, in step **384**, and scanning is conducted based on the second radiation pulse pattern, in step **386**. The detected radiation is analyzed in step **388**.

FIG. **7** is an example of a method **391** for changing conveyor speed in accordance with an embodiment of the invention. An object is scanned while the conveyor **116**, **116a** and/or **116b** is moved at a first conveyor speed, in step **390**. The results are analyzed in step **392**. The first conveyor speed is changed to a second conveyor speed, in step **394**. The object is scanned at the second conveyor speed, in step **396**, and the results are analyzed, in step **398**.

FIG. **8** is a schematic diagram of another example of an embodiment of a compact system **300** for examining objects with radiation at least two energies. In this example, one radiation source **302**, which generates radiation at two or more energies, is positioned, horizontally, adjacent to a support **306**, which may be a conveyor **306** with a surface **306a**. One of the energies may be 9 MeV and the other energy may be 6 MeV, or one of the energies may be 6 MeV and the other 1 MeV, for example. In this example, the radiation beams are emitted at comparable dose rates, but that is not required. In FIG. **8**, a long axis **307** of the linear accelerator **302** is parallel to the direction of movement C of the object **308** to be examined. The linear accelerator **302** may be positioned vertical and perpendicular to the direction of movement C of the object **308** and to a plane containing a surface **306a** of the conveyor, as in FIG. **5**, for example. As above, the object **308** may be a cargo conveyance. Also as above, conveying systems **309a**, **309b**, shown in phantom, which may be separate or connected to each other, may be provided to move the radiation source **302** and detector **320** past the object **308** instead of moving the object.

The radiation source **302** comprises the linear accelerator **304**, a bend magnet system **310**, a target assembly **312** housing a target **313**, and a collimator **315**. The linear accelerator **304** is coupled to the bend magnet system **310** through a drift tube **314** and the bend magnet system is coupled to the target assembly **312** through a drift tube **316**, all of which are under vacuum. The remaining structure of the target assembly **312** is the same as that of the target assemblies **142**, **144** of FIG. **2** and is not further described here.

The linear accelerator **302** of FIG. **8** provides accelerated charged particles, such as electrons, through the drift tube **314** into the bend magnet system **310**, such as one of the 270 degree achromats described above, which deflects the beams of accelerated charged particles towards a target **313** through the drift tube **316**. In this example, the same bend magnet system **310** turns both beams of accelerated charged particles through a single orbit chamber, as discussed below.

Impact of the beam on the target **308** causes generation of radiation by the Bremsstrahlung effect, as is known in the art. The Bremsstrahlung X-ray radiation is emitted from the target **313** in all directions, with an angular distribution dependent upon the energy of the incident beam charged particles and the target, as is known in the art. The radiation emitted in the direction of the collimator **315** is collimated into the desired shape and emitted from the radiation source

302, toward the object 308. After interacting with the object 308, the radiation is detected by the detector 320, which may be a detector array. The detector 320 is coupled to a processor 322, which is coupled to a display 324, as above. The processor 324 or another processor may be coupled to the radiation source 304, the detector 320, and to the conveyor 306, 309a, 309b control their operation, as well. The detector 320 may be a detector array, for example. Additional circuitry, such as analog-to-digital circuitry, may be provided between the detectors 320 and the processor 124, as is known in the art. The processor 322 may be a logic circuit, such as an ASIC or FPGA, a programmable logic controller, or a microprocessor, for example.

As mentioned above, in this example, the bend magnet system 310 turns both the higher and lower energy beams of accelerated charged particles toward the target 313 through the same orbit chamber. FIG. 9 is a schematic representation of two beam paths, one for a low, 6 MeV electron beam, and the other for a high, 9 MeV electron beam, turned 270 degrees by the bend magnet system 310 toward the target 313. Since the beam of charged particles accelerated to the higher energy, in this example 9 MeV, has greater kinetic energy, it must be turned over a wider radius than the lower energy beam, in this example 6 MeV, as is known in the art.

Also shown schematically in FIG. 9 are energy slits 333, 334, 335 that act as beam stops to intercept charged particles whose energies deviate from the desired acceleration energies (of 9 MeV and 6 MeV, for example), and whose radial displacements vary due to dispersion. The steps 333, 334, 335 define "energy slits" through which the charged particles of the desired energy ranges pass. For example, the energy slits 333, 334, 335 may be configured to remove charged particles with energies $\pm 3\%$ of the desired central energy for each beam. In the case of the 9 MeV electron beam, electrons with energies greater than about 9.3 MeV and less than about 8.7 MeV may be removed, for example.

FIG. 10 is an example of an orbit chamber 350 that may be used in the bend magnet system 310 to define a path for two different charged particle beams accelerated to two different energies. The orbit chamber 350 defines an inlet 352, an outlet 354, and a first passage 356 extending to a wall 358 that bifurcates the passage into two passages 360 and 362. The passages 360, 362 may merge into a single passage 363 near the outlet 354. The charged particle beam with the lower energy is bent over a smaller radius, through the passage 360, and the charged particle beam with the higher energy is bent over a larger radius, through the passage 362, as described above with respect to FIG. 9. The passages 360, 362 each curve around 270 degrees toward the outlet 354, as described above with respect to FIG. 4. As above, the orbit chamber 350 may comprise oxygen-free, electronic grade copper, which defines the passage 356. The inlet 352 to the orbit chamber 350 is coupled to the drift tube 314 and the output 354 of the orbit chamber is coupled to the drift tube 316.

Each passage 360, 362 may include a first, wider portion 360a, 362a extending from the inlet 352 to narrower choke sections 364, 366, respectively, followed by wider portions 368, 370 extending from the choke sections toward the outlet 354. The choke sections 364, 366 are defined by portions 333, 334, 335 of the orbit chamber that extend into the passages 360a, 362a. As discussed above, the choke sections 364, 366, which are optional, may be provided in each passage 360, 362 to provide beam stops to remove dispersed charged particles, such as electrons, with energies above and below the desired energy, as discussed above.

The orbit chamber 350 sits within a magnet system, as described above with respect to FIG. 3, or the other examples described above, for example. As above, two different magnetic fields may be applied to the orbit chamber 350 to achieve the desired curvature of the respective charged particle beams, also as described above. In FIG. 10, a line 375 represents a step or change in the magnetic fields between a low magnetic field in a region A through the orbit chamber 350, and a high magnetic field in a region B through the orbit chamber. The beam of charged particles is therefore first deflected by the low magnetic field in region A. When the step is crossed, the beam is subjected to a high magnetic field in region B and deflected a greater amount. When the beam returns to region A, the beam is again subjected to the low magnetic field. Due to the dispersion caused by the approximately achromatic stepped field angle, the two different beams charged particles may impact the target 313 up to several millimeters apart. The separation may be compensated for during analysis of the data so that the same or substantially the same scanning slices at the different energies may be compared, ratioed, etc. When the orbit chamber is arranged such that the separation is along the direction of movement of the object 308 (or the source 302 and the detector 320), the speed of movement of the object (source and detector) may compensate, at least in part, for the separation. Alternatively, a non-stepped, varying magnetic field may be used, such as an Enge magnet, which has less or no dispersion, as is also described above.

FIG. 11 is a schematic representation of an example of a radiation source 400 that may be switched between accelerating charged particles, such as electrons, to different energies, such as 9 MeV and 6 MeV, or 6 MeV and 1 MeV, for example, to generate radiation beams having energies of 9 MV and 6 MV, or 6 MV and 1 MV, respectively, for example. 9 MeV and 6 MeV, or 6 MeV and 1 MeV, the source 400 comprises an accelerator 402, such as a linear accelerator, and a source of charged particles 404, such as an electron gun, at an input end of the accelerator.

A microwave power source, such as a klystron 406, provides microwave or radio frequency (referred to generically as "rf") power to the accelerator 402. The klystron 406, which comprises a vacuum tube, is driven by an rf driver 408, as is known in the art. The rf driver 408 provides a programmable or selectable rf signal or pulse to the klystron 406 to modulate the rf field within the klystron. The signal may have a 20 Watt to 200 Watt peak power with a carrier frequency of 2856 MHz, 2998 MHz, or 9300 MHz, for example. The pulsed amplitude modulated signal may have a pulse width of 1 microseconds to 5 microseconds and a pulse repetition frequency of 50 Hz to 2000 Hz, with a duty factor of 0.004 to 0.005, for example.

A processor 410 provides a voltage trigger pulse to the rf driver 408 along line 412, to synchronize the rf driver output to the klystron 406. The processor 410 also provides inputs to the rf driver 408 to set the amplitude and frequency of the rf drive pulse provided along the line 412. A sensor 406a is provided in the klystron 406 to detect the current in the klystron. The processor 410 monitors the klystron current along a line 413. The processor 410, which may be the same as the processor 322 or another such processor, may be a logic circuit, such as an ASIC or FPGA, a programmable logic controller, or a microprocessor, for example. An automatic frequency control (not shown) may also be provided to provide closed logic feedback to the rf driver 408 to keep it locked on the accelerator resonance frequency, which can shift due to thermal transients and other accelerator perturbations. Automatic frequency control techniques are dis-

cussed in U.S. Pat. No. 8,183,801, which was filed on Aug. 12, 2008, is assigned to the assignee of the present invention, and incorporated by reference herein, for example.

The klystron **406** is also driven by a high voltage pulse modulator **414**, which provides high power pulses to the klystron to establish the voltage on the klystron gun (not shown). The modulator **414** comprises a high voltage power supply and a pulse forming network (not shown), as is known in the art. An optional pulse transformer **416** may be provided to increase the voltage of the pulses provided to the klystron **406**. For example, the modulator **414** may output 20 kV pulses that are increased to 120 kV by the pulse transformer **416**. The processor **410** provides a modulator trigger pulse to the modulator **414** along line **418**, to cause the modulator to start and stop generating each high voltage pulse. The voltage in the klystron **406**, established by the voltage power pulses provided by the modulator **414**, generates a high-current electron beam, which is subsequently modulated by the rf voltage pulses provided by the rf driver **408** to the klystron input cavity and by subsequent interaction with the klystron cavities, as is known in the art.

The accelerator electron gun **404** in this example is a triode gun, comprising a grid, an anode, and a cathode (not shown), as is known in the art. The electron gun **404** is driven by a gun driver **420**, under the control of the processor **410**. The grid of the gun **404** may be used to adjust the electron current from the gun to the accelerator **402**, including disabling current. Changing the beam current changes the dose rate of the resulting radiation beams, and changes the beam energy by "beam loading," as is known in the art. The gun driver **420** provides a DC high voltage to the gun along line **422** and a lower voltage to the grid, along line **424**. The DC voltage may be 3 kV to 30 kV, for example. The grid voltage (referenced to the cathode) may be -200 V to 400 V, for example. Typical beam perveance may be up to 0.3 μperv , depending on the grid setting. The processor **410** turns the gun driver **420** on and off via a gun trigger line **426** and defines the length of a pulse of electrons, along a gun pulse width line **428**. The processor **410** also sets the high DC voltage to be provided to the electron gun **404**, to the gun drive **420** along another line (not shown).

In this example, the high voltage signal along line **422** establishes a constant DC voltage between the anode and the cathode of the gun **404**. The grid voltage is varied by providing three different voltage pulses to the grid, one voltage to turn the gun off, and two different voltages to define different beam currents during generation of each radiation beam, so that the dose rate of the radiation beams at the different energies are comparable.

In another example, the constant, high voltage defines one beam current, without providing a voltage pulse to the grid, and the other beam current is defined by providing a voltage pulse to the grid (with the constant high voltage also present). In another example, the amplitude of the high voltage pulse is varied or turned off by varying the amplitude of the high voltage pulse along line **422**, as well as varying the grid voltage, along line **424**.

The gun driver **420** comprises a fast circuit that changes the grid voltage levels on a pulse-to-pulse basis. The grid voltage levels may be changed on the order of 300 Hz to 400 Hz or faster, for example. The rate may be in kilohertz, for example. The processor **410** communicates with the gun driver **420** to set the level of the next voltage pulse to the grid, about 100-200 microseconds prior to the trigger of that pulse. The next voltage pulse may be the same or different, depending on the pattern of radiation to be generated.

To change the acceleration energy of the linear accelerator **402** from one nominal energy to another nominal energy, rf power provided to the accelerator **402** by the klystron **406** is varied, as is the voltage provided to the grid in the electron gun **404**. The acceleration energy of the electrons and the energy of the generated radiation, are thereby changed.

FIG. **12** is an example of a timing diagram for the radiation source **400** of FIG. **11**, implemented by the processor **410** to switch the acceleration energy of the linear accelerator **402**. After an rf delay of from about 0.1 to about 0.5 microseconds, the processor **410** triggers the rf trigger to the rf driver **408**, along line **412** (see FIG. **9**), at a time T1.

After a modulator delay of about 500 nanoseconds after the rf trigger is triggered, the processor **410** triggers the modulator trigger to the modulator **414**, along line **418**, at time T2.

Electrons are emitted into the accelerator **402** by the electron gun **404** when the klystron **406** is at the peak current, which takes place when the modulator pulse is at a peak voltage, in this example. Since it takes time for the voltage amplitude of the modulator **414** to rise to its peak value, such as 20 kV, for example, in this example the processor **410** triggers the gun trigger pulse along line **426** at a time 500-600 nanoseconds from the time a predetermined reference current is detected in the klystron **406** by the processor **410** (along line **413** in FIG. **6**), to allow the modulator to reach the peak voltage. In this example, the gun delay is a predetermined time period starting from a time T3, when the klystron **406** current reaches a predetermined value, to a time T4. As discussed above, the processor **410** monitors the klystron current via the sensor **406** along the line **413**, shown in FIG. **6**.

The gun trigger pulse starts at the time T4 and ends at a time T5. The length of the gun trigger pulse in this example is from 1.0-4.5 microseconds. The start of the gun trigger pulse may be delayed to decrease the length of the beam pulse.

In this example, the modulator pulse starts to fall about 5.5 microseconds after being triggered, at a time T6. The rf pulse is turned off 6 microseconds after being triggered, at a time T7.

The process is then repeated to generate the next radiation pulse, by providing the same or a different rf voltage power pulse from the rf driver **408** to the klystron **406** and providing the same or different voltage pulse from the gun driver **420** to the electron gun **404**, depending on whether the next radiation pulse to be generated by the radiation source **300** is to have the same or a different energy than the prior radiation pulse. A third, different rf voltage pulse may be provided by the rf driver **420** to the klystron **406** and a third, different voltage pulse may be provided from the gun driver **420** to the electron gun to accelerate charged particles to a third energy to generate radiation pulses to a third energy at a comparable dose rate as the first and second radiation pulses.

A desired radiation pulse pattern may be generated by providing a corresponding rf drive pulse pattern to the klystron **406** from the rf driver **408**, and corresponding voltage pulse pattern to the grid from the gun driver **420**, under the control of the processor **410**. As discussed above, one example of a radiation pulse pattern is alternating high and low radiation pulses, each with comparable dose output levels for both the high and low energy radiation beams. Any pulse patterns may also be implemented by the single radiation system, including the others discussed above.

In another example of driving an accelerator to accelerate electrons to two or more different energies to generate

radiation at two or more respective energies, the rf output power of the klystron **406** may be varied by changing the high voltage on the klystron via the modulator **414**, and keeping the output power of the rf driver **408** fixed. Instead of the klystron **406**, the accelerator **402** may be driven by a magnetron.

Klystron and magnetron multi-energy radiation sources that may be used herein are also described in U.S. Pat. No. 8,183,801, which was filed on Aug. 12, 2008, is assigned to the assignee of the present invention, and incorporated by reference herein. A diode gun may be used instead of the triode gun **404**, as is known in the art and is also described in U.S. Pat. No. 8,183,801. The diode gun may be used with a high voltage pulsed modulator, for example. The high voltage pulse modulates the beam current directly. Alternatively, triode modulated-anode, or other electron emitters, may be used with a high voltage pulsed gun modulator.

Instead of the accelerator described above, an electrical energy switch and/or power variator may be used to accelerate charged particles at different energies in an interleaved fashion, as described in U.S. Pat. No. 8,143,816, which was filed on Aug. 13, 2008, and U.S. Pat. No. 7,786,823, which was filed on Jun. 26, 2006, both of which are assigned to the assignee of the present invention and are incorporated by reference herein.

In another example, the support **306** may be a rotating platform and the radiation source **302**, the detector **320**, and/or the rotating platform may be movable vertically.

The dual energy test results may be analyzed, as discussed above. The radiation pulse sequence implemented by the single radiation source **400**, as well as the conveyor speed, may also be changed, as described above, but in this case, the new radiation pulse sequence is generated by the same radiation system **400**, under the control of the processor **410**. In addition, the change in the radiation pulse sequence may include changing the dose rate at one or both radiation energies. The dose rate may be changed by changing the voltage provided to the grid of the electron gun **404** by the gun driver **420**, or by other techniques described above, for example.

One of ordinary skill in the art will recognize that changes may be made to the embodiments described above without departing from the spirit and scope of the invention, which is defined by the claims, below.

We claim:

1. A method of conducting radiation scanning of an object, comprising:

scanning an object with a first radiation beam pulse pattern comprising at least one of at least two different radiation beams, each having a different characteristic; moving the object at a first conveyor speed while scanning the object;

detecting first radiation after interaction of the first radiation beam pulse pattern with the object;

analyzing the detected first radiation; scanning the object with a second radiation beam pulse pattern different from the first radiation beam pulse pattern, if suspect material is at least potentially identified;

moving the object at a second conveyor speed different than the first conveyor speed, if suspect material is at least potentially identified;

detecting second radiation after interaction of the second radiation beam pulse pattern with the object; and analyzing the detected second radiation.

2. A method of examining objects by radiation, comprising:

directing a first radiation beam pulse pattern toward an object;

detecting first radiation after interaction of the first radiation beam pulse pattern with the object;

analyzing the detected first radiation;

if a potentially suspect region is identified prior to completing scanning of the entire object, changing the first radiation beam pulse pattern to a second radiation beam pulse pattern, the second radiation beam pulse pattern being based, at least in part on the detected first radiation:

directing the second radiation beam pulse pattern toward the object;

detecting second radiation after interaction of the second radiation beam pulse pattern with the object;

analyzing the detected second radiation;

when scanning of the potentially suspect region is completed, changing the second radiation beam pulse pattern to the first radiation beam pulse pattern; and

resuming direction of the first radiation beam pulse pattern toward the object to continue examination of the object.

3. A method of examining objects by radiation, comprising:

directing a first radiation beam pulse pattern toward an object;

detecting first radiation after interaction of the first radiation beam pulse pattern with the object;

analyzing the detected first radiation;

directing a second radiation beam pulse pattern toward the object, the second radiation beam pulse pattern being based, at least in part on the detected first radiation;

detecting second radiation after interaction of the second radiation beam pulse pattern with the object; and

analyzing the detected second radiation;

wherein:

the first radiation beam pulse pattern comprises alternating high and low energy pulses; and

the second radiation beam pulse pattern comprises only low energy pulses.

4. The method of claim 3, further comprising:

moving the object at a first conveyor speed while directing the first radiation beam pulse pattern toward the object; and

moving the object at a second conveyor speed different than the first conveyor speed, if suspect material is at least potentially identified.

5. A method of examining objects by radiation, comprising:

directing a first radiation beam pulse pattern toward an object;

detecting first radiation after interaction of the first radiation beam pulse pattern with the object;

analyzing detected first radiation;

directing a second radiation beam pulse pattern toward the object, the second radiation beam pulse pattern being based, at least in part on the detected first radiation;

detecting second radiation after interaction of the second radiation beam pulse pattern with the object; and

analyzing the detected second radiation;

wherein:

the first radiation beam pulse pattern comprises only high energy pulses; and

the second radiation beam pulse pattern comprises only low energy pulses.

6. A method of examining objects by radiation, comprising:

19

directing a first radiation beam pulse pattern toward an object;
 detecting first radiation;
 analyzing the detected first radiation;
 directing a second radiation beam pulse pattern toward the object, the second radiation beam pulse pattern being based, at least in part on the detected first radiation;
 detecting the second radiation after interaction of the second radiation beam pulse pattern with the object;
 and
 analyzing the detected second radiation;
 wherein:
 the first radiation beam pulse pattern comprises only low energy pulses; and
 the second radiation beam pulse pattern comprises only high energy pulses.

7. The method of claim 2, wherein:
 the first radiation beam pulse pattern comprises only high energy pulses or only low energy pulses; and
 the second radiation beam pulse pattern comprises alternating high and low energy pulses.

8. A method of examining objects by radiation, comprising:
 directing a first radiation beam pulse pattern toward an object;
 detecting first radiation after interaction of the first radiation beam pulse pattern with the object;
 analyzing the detected first radiation;
 directing a second radiation beam pulse pattern toward the object, the second radiation beam pulse pattern being based, at least in part on the detected first radiation;
 detecting the second radiation after interaction of the second radiation beam pulse pattern with the object;
 and
 analyzing the detected second radiation;
 wherein:
 the first radiation pulse pattern comprises radiation having a first dose rate; and
 the second radiation pulse pattern comprises radiation having a second dose rate different from the first dose rate.

9. The method of claim 2, further comprising:
 accelerating first charged particles to a first energy;
 bending the first charged particles toward a first target;
 generating a first radiation beam having a second energy from impact of the first charged particles on the target;
 accelerating second charged particles to a third energy different than the first energy;
 bending the second charged particles toward a second target;
 generating a second radiation beam having a fourth energy different from the second energy from impact of the second charged particles on the second target;
 directing at least one of the first and second radiation beams toward the object in accordance with the first pulse pattern; and
 directing at least one of the first and second radiation beams toward the object in accordance with the second pulse pattern.

10. The method of claim 9, comprising:
 accelerating the first and second charged particles by first and second, separate, accelerators; and
 bending the first and second charged particles by first and second, different magnet systems.

11. The method of claim 9, comprising:
 accelerating the first and second charged particles by a single accelerator;

20

bending the first and second accelerated charged particles toward the same target by a magnet system; and
 generating the first and second radiation beams from impact of the first and second accelerated charged particle beams on the same target.

12. The method of claim 11, comprising:
 bending the first and second charged particle beams around respective, different, radii through an orbit chamber defining at least partially separate passages extending at least partially through the orbit chamber, for each charged particle beam.

13. A radiation generation system comprising:
 a support to support an object;
 at least one radiation source to direct radiation toward a target;
 at least one detector to detect radiation after interacting with the object; and
 a processing device configured to:
 cause the at least one radiation source to generate radiation in accordance with a first pulse pattern to be directed toward the object; and
 cause the at least one radiation source to generate radiation in accordance with a second pulse pattern to be directed toward the object, the second pulse pattern being different from the first pulse pattern, the second pulse pattern being based, at least in part, on radiation detected after interaction of the first pulse pattern with the object;
 wherein the support comprises:
 a conveyor system to move the object through the directed first and second radiation, during scanning; and
 the processing device is configured to cause the conveyor system to move the object at a first speed during the first pulse pattern and at a second speed different from the first speed based, at least in part, on detected radiation.

14. The radiation generation system of claim 13, wherein:
 the at least one radiation source comprises:
 a first radiation source configured to generate first radiation having a first energy; and
 a second radiation source configured to generate second radiation having a second energy different from the first energy; and
 the first pulse pattern comprises at least one of the first radiation and the second radiation; and
 the second pulse pattern comprises at least one of the first radiation and the second radiation.

15. The radiation generation system of claim 14, wherein the processing device is configured to selectively cause:
 the first radiation source to generate a first radiation beam having the first energy; and/or
 the second radiation source to generate a second radiation beam having the second energy,
 during the first and second pulse patterns.

16. The radiation generation system of claim 14, wherein the first and second radiation sources respectively comprise:
 first and second charged particle sources;
 first and second accelerators to accelerate the first and second charged particles to first and second energies, respectively;
 first and second respective targets;
 a first bend magnet positioned to receive the accelerated first charged particles along a first axis from the first accelerator and to direct the first charged particles toward the first target along a second axis different from the first axis; and

21

a second bend magnet positioned to receive the accelerated second charged particles from the second accelerator along a third axis and to direct the second charged particles toward the second target along a fourth axis different from the third axis.

17. The radiation generation system of claim 14, wherein the at least one radiation source comprises a single radiation source configured to generate the first radiation beam and the second radiation beam.

18. The radiation generation system of claim 17, wherein the radiation source comprises:

a source of charged particles;

a charged particle accelerator having an input coupled to the source of charged particles to receive the charged particles, and an output to allow accelerated charged particles to exit the accelerator along a first axis;

the charged particle accelerator configured to generate a first beam of accelerated charged particles having a first energy and a second beam of accelerated charged particles having a second energy different than the first energy;

a target positioned along a second axis different than the first axis;

a magnet system along the first axis, configured to deflect the first and second accelerated charged particles through first and second at least partially separate passages, along the second axis, toward the target;

wherein impact of the first charged particle beam on the target causes generation of a first radiation beam having a first energy and impact of the second accelerated charged particle beam on the target causes generation of a second radiation beam having a second energy different than the first energy.

19. The radiation scanning system of claim 18, wherein the magnet system comprises:

22

an orbit chamber defining;

an inlet;

an outlet; and

a passage coupling the inlet to the outlet, the passage configured to allow passage of the first accelerated charged particle beam and the second accelerated charged particle beam from the inlet to the outlet.

20. The radiation scanning system of claim 19, wherein the orbit chamber further defines:

a wall in a portion of the passage separating a portion of the first passage from a portion of the second passage to define separate passages at least partially through the orbit chamber for the first charged particle beam and the second charged particle beam, respectively.

21. The radiation scanning system of claim 13, further comprising:

a conveying system to move at least one of the at least one detector and the radiation sources past the object.

22. The method of claim 3, further comprising: determining that low density material is present based on the analysis of the radiation detected during the first pulse pattern; and

directing the second radiation pulse pattern comprising low energy pulses, if it is determined that low density material is detected.

23. The method of claim 5, further comprising: determining that the high density material is present based on the analysis of the radiation detected during the first pulse pattern; and

directing the second radiation pulse pattern comprising high energy pulses, if it is determined that high density material is detected.

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